

III-V-ON-SI SOAS AND DFB/DBR LASERS REALISED USING MICRO-TRANSFER PRINTING

Bahawal Haq

LIGHT AS WE SEE IT!



Dispersion



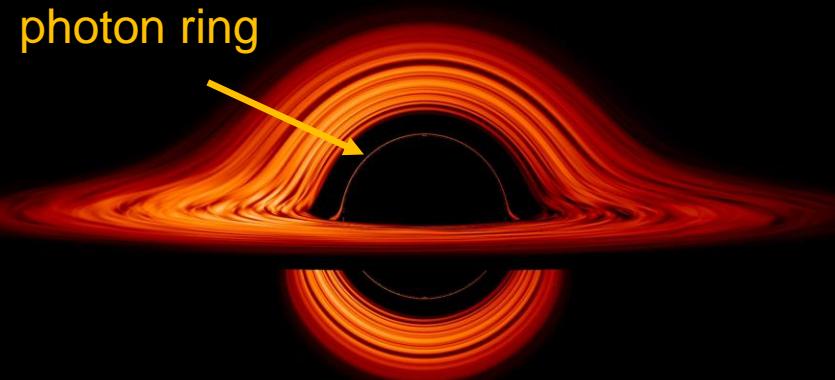
Reflection



Scattering

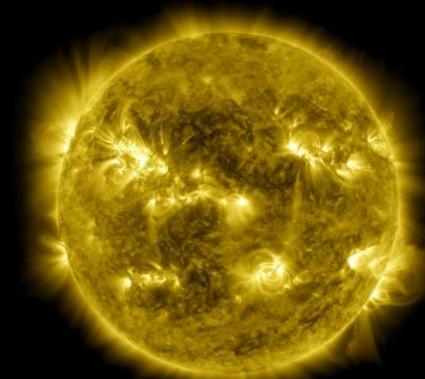
MARVELS OF LIGHT

Light interacts with matter at every scale

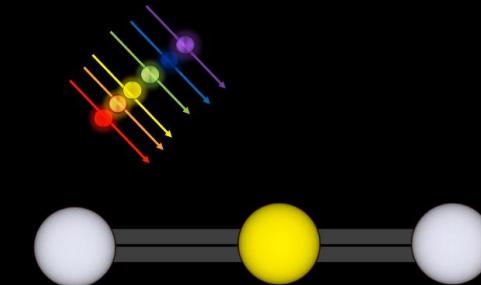


NASA's Goddard Space Flight Center

2011 Sep 16



NASA's Goddard Space Flight Center

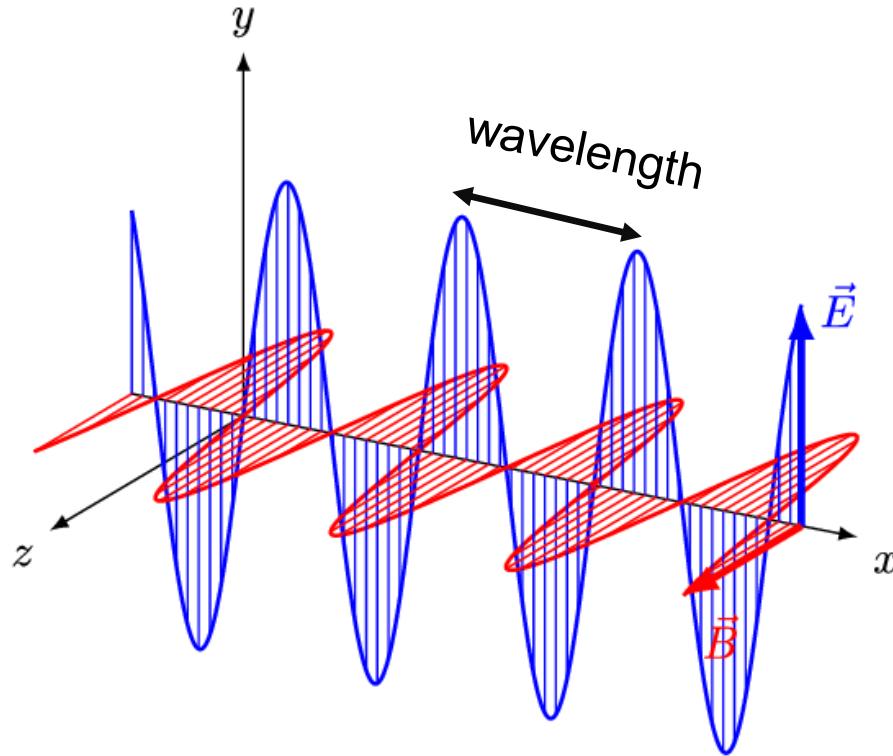


Vibrational mode of gas molecules

From celestial bodies to molecules

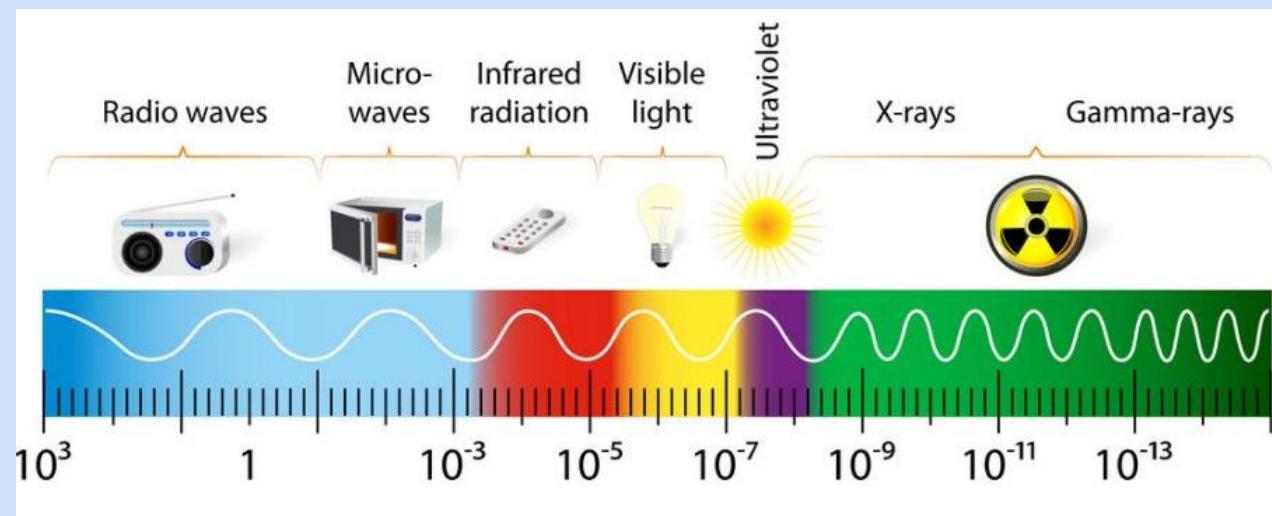
PHYSICS OF LIGHT

Electric and magnetic fields

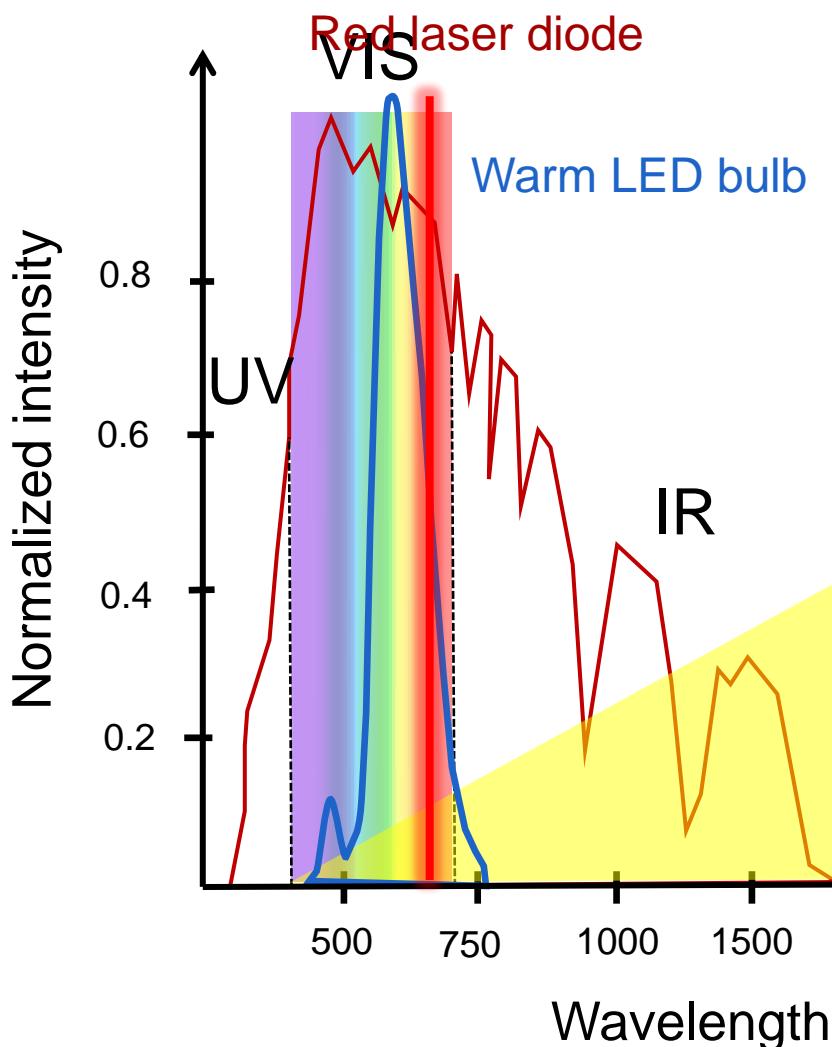


And1mu, CC BY-SA 4.0 <<https://creativecommons.org/licenses/by-sa/4.0>>, via
Wikimedia Commons

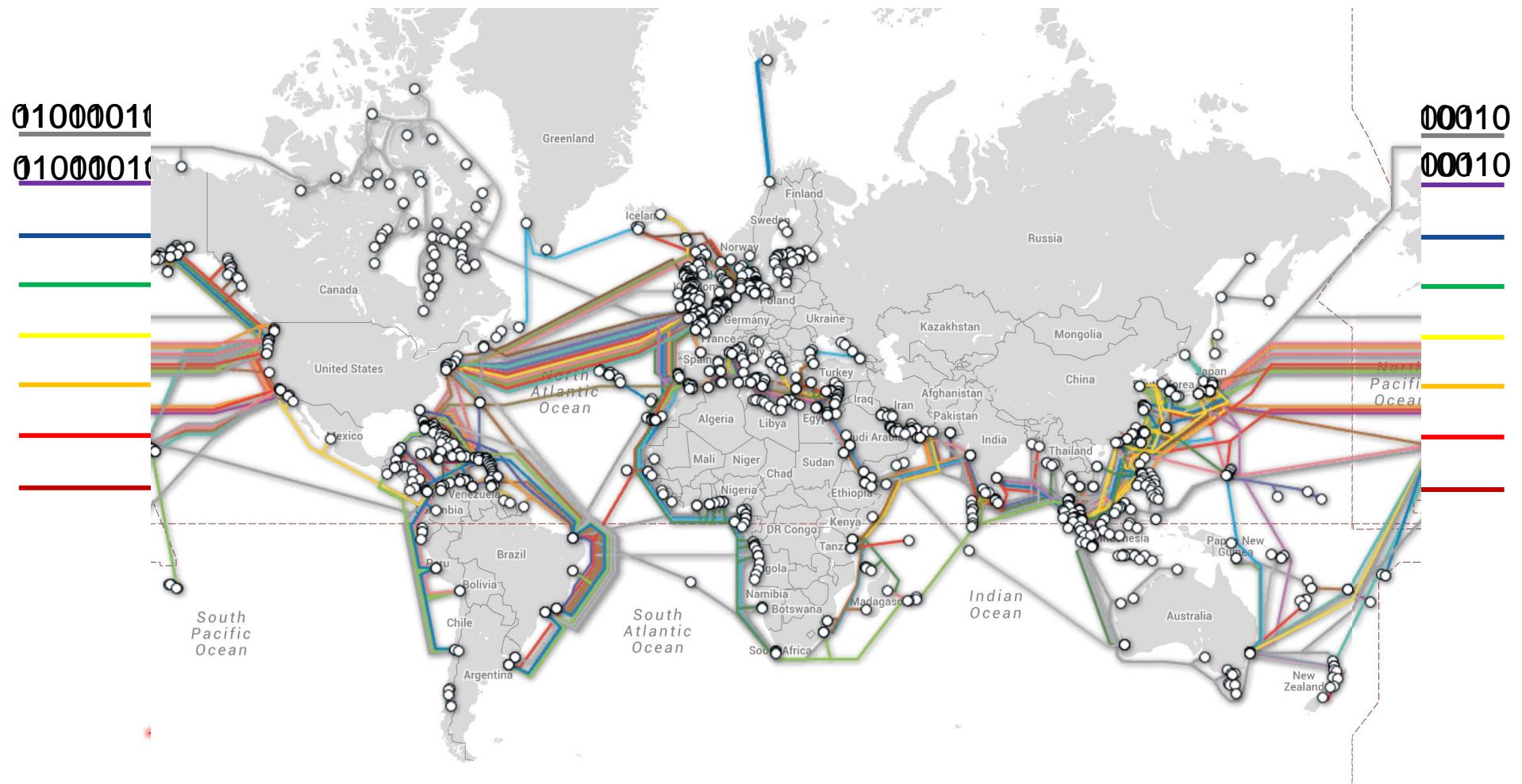
Electromagnetic Spectrum



SPECTRUM OF COMMON SOURCES

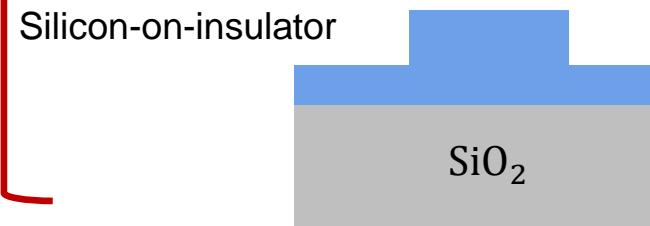
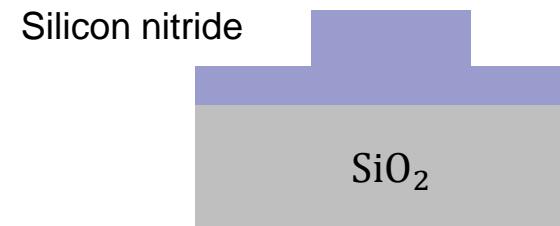
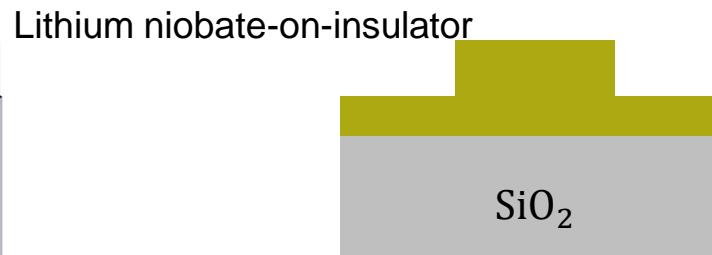
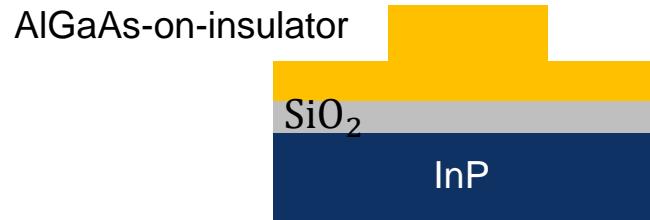
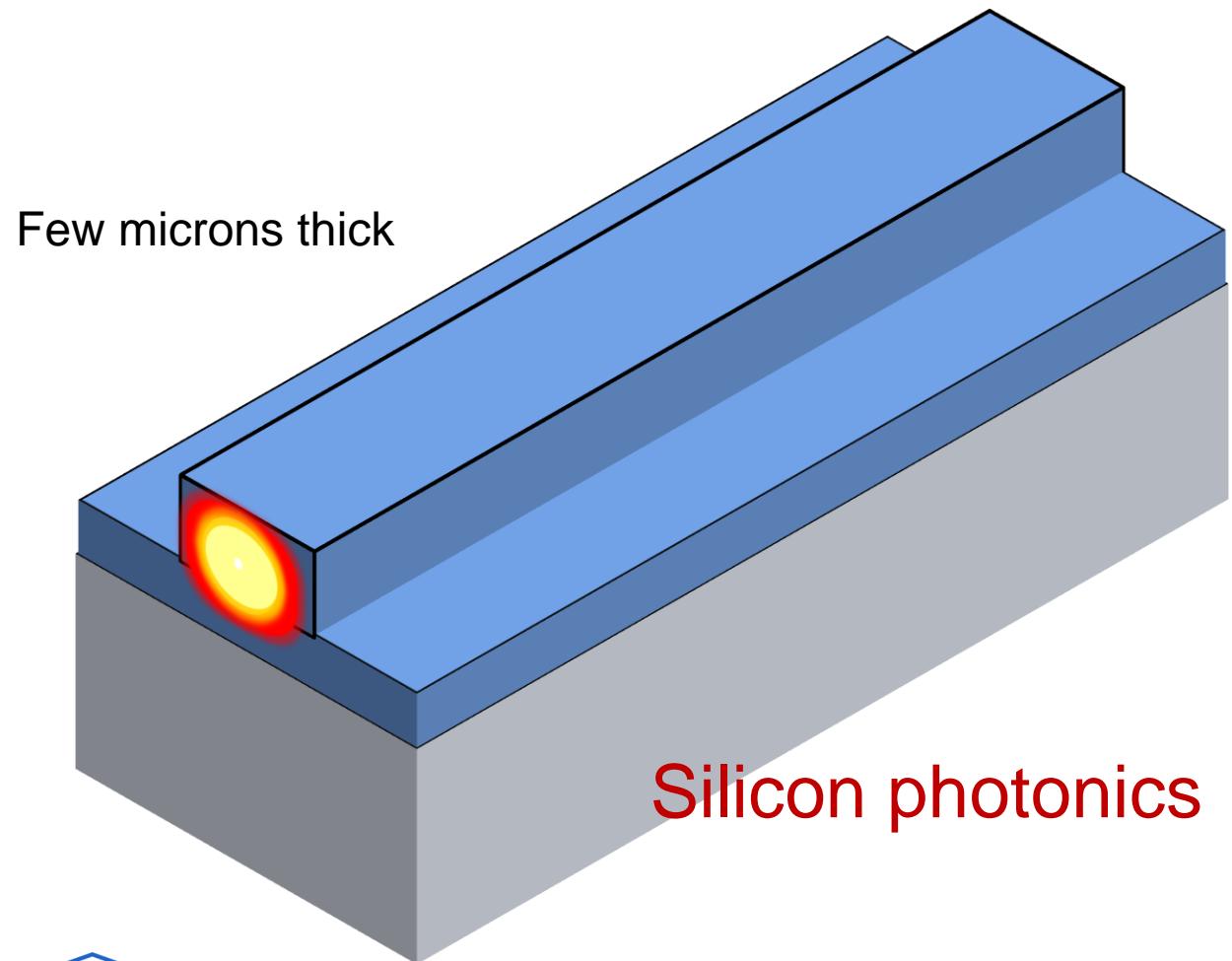


OPTICAL COMMUNICATION



Underwater fiber optics network connects the world

LIGHT CAN BE GUIDED ON-CHIP



- Excellent non-linear properties
- Both active and passive devices are possible
- Mostly used in R&D
- High cost and low volume

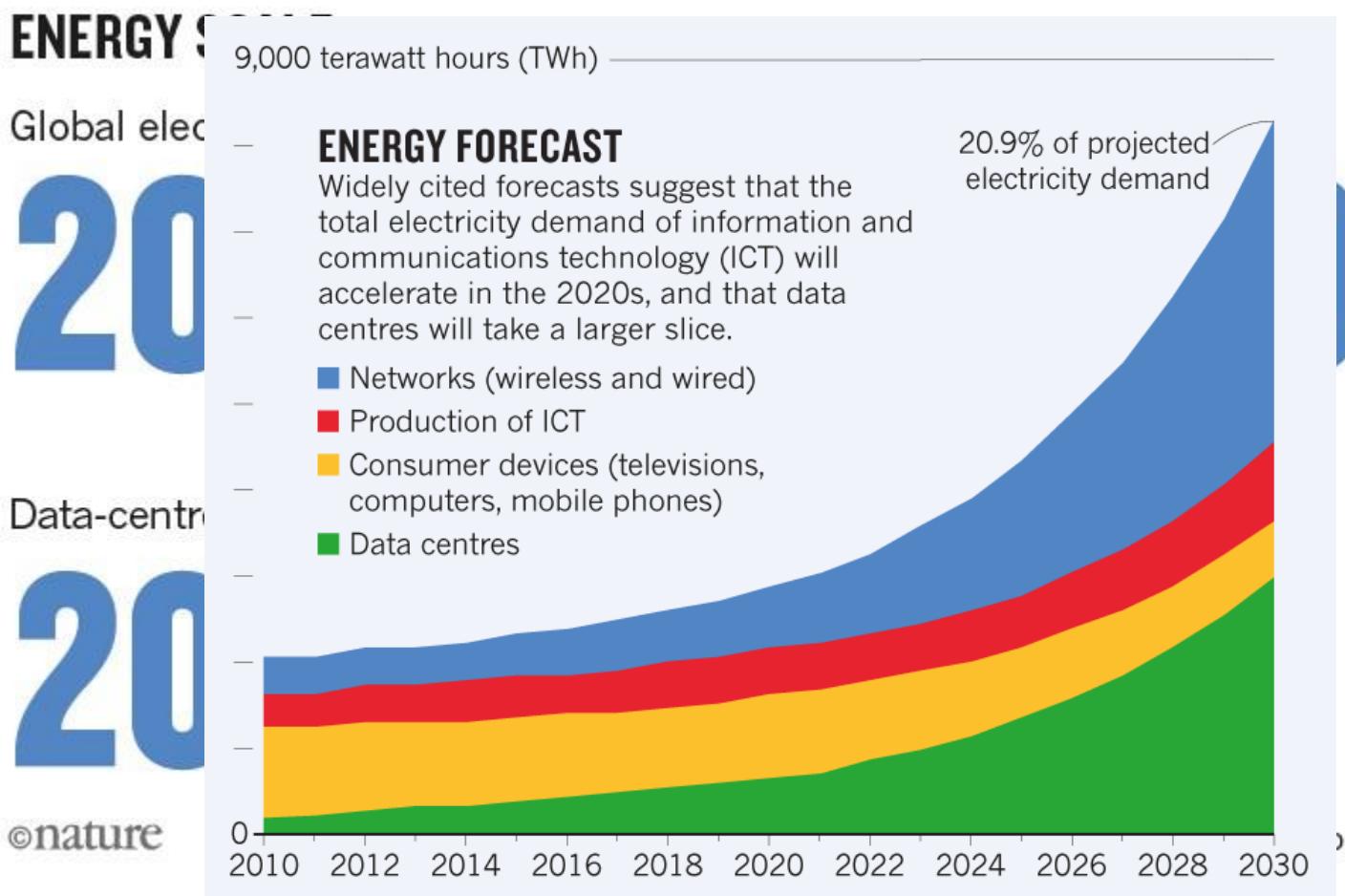
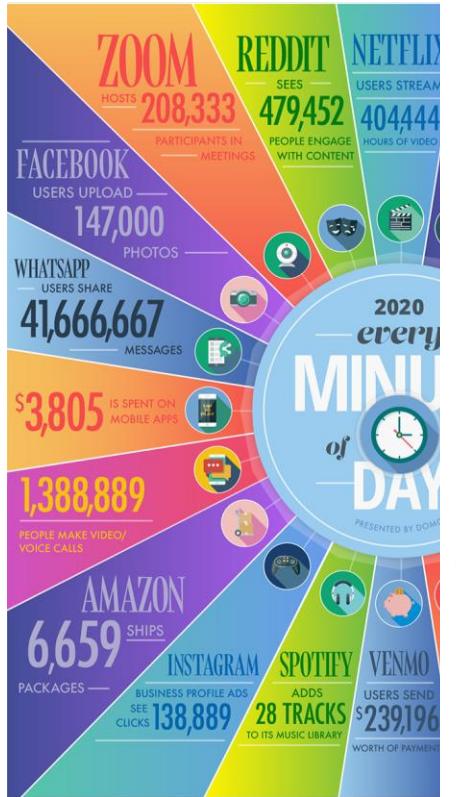
- Good Electro-optic and acoustic-optic properties
- Not mature platform, still under development

- CMOS compatible
- Relatively mature
- Ultra-low loss platform
- Larger bend radii and lower density of integration

- CMOS compatible and mature ecosystem
- Monolithic electronics-photonics integration
- Inefficient light sources

WHY GO ON-CHIP? (1)

Astronomical amount of data



ata
en servers which
erates heat.

TO PUT INTO CONTEXT



60 mins of video streaming

<https://www.carbonbrief.org/factcheck-what-is-the-carbon-footprint-of-streaming-video-on-netflix>



1.1 Km

Running distance
for a 75 Kg person

<https://www.runningtools.com/energyusage.htm>



WHY GO ON-CHIP? (2)

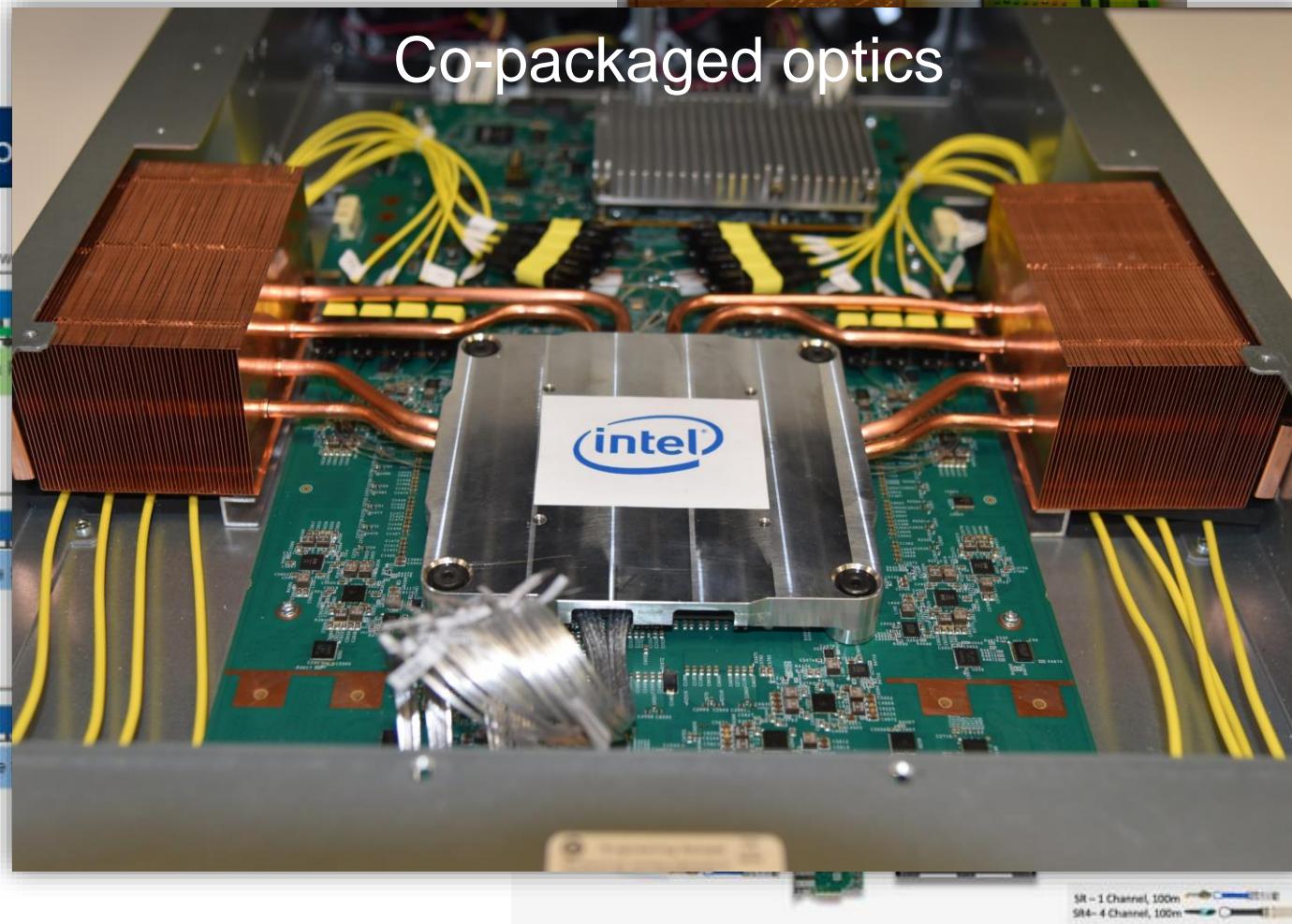


Co-packaged optics

Optical communication

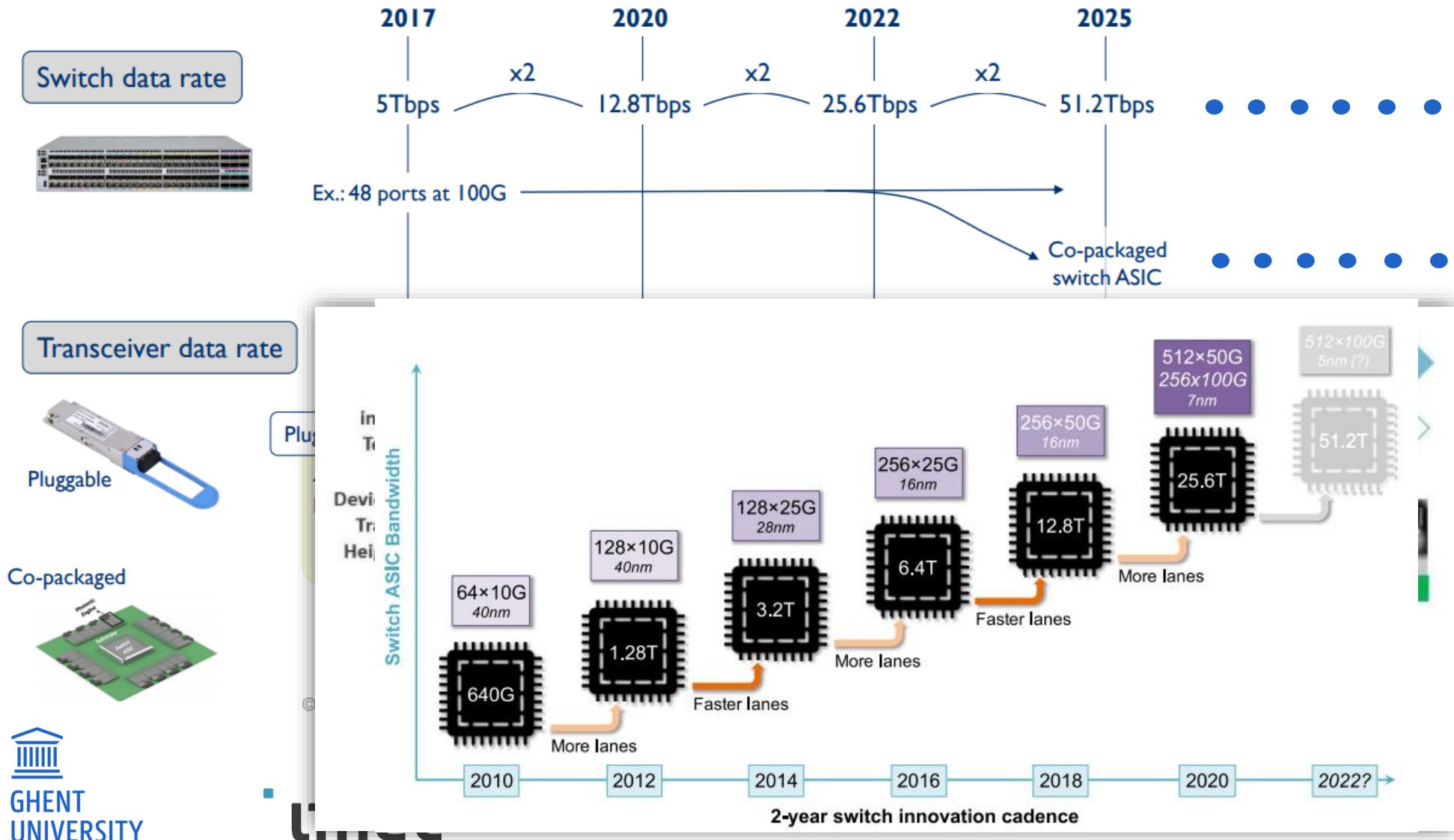
Including optical transceivers, optical interconnects, co-packaged photonic engines

- It allow us to n and inexpensive modules



Integration of 1.6 Tbps silicon photonics engine with its 12.8 Tbps programmable Ethernet switch.

WHAT'S NEXT



20xx

Moore's Law will continue

More intimate integration (modular)

Faster, smaller and cheaper

THERE IS MORE TO IT! (LIDAR)



iPhone 12 pro



Lighter, smaller and cheaper

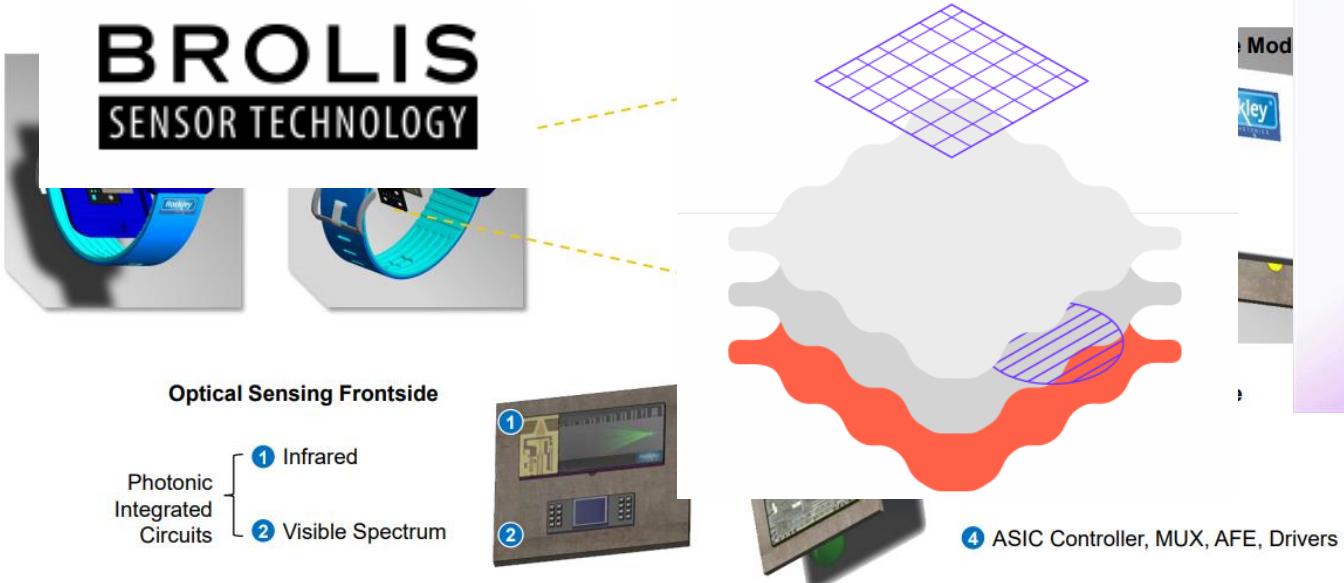
➤ Bulky with expensive optics



AND MORE! (HEALTHCARE)

Si Photonics in action

BROLIS
SENSOR TECHNOLOGY



Transdermal sensing of blood for glucose, lactate and ethanol



UNIVERSITY



Disclaimer: This is not a medical device. This is not a product. This is a mock-up.

Continuous Glucose Monitoring (CGM) systems

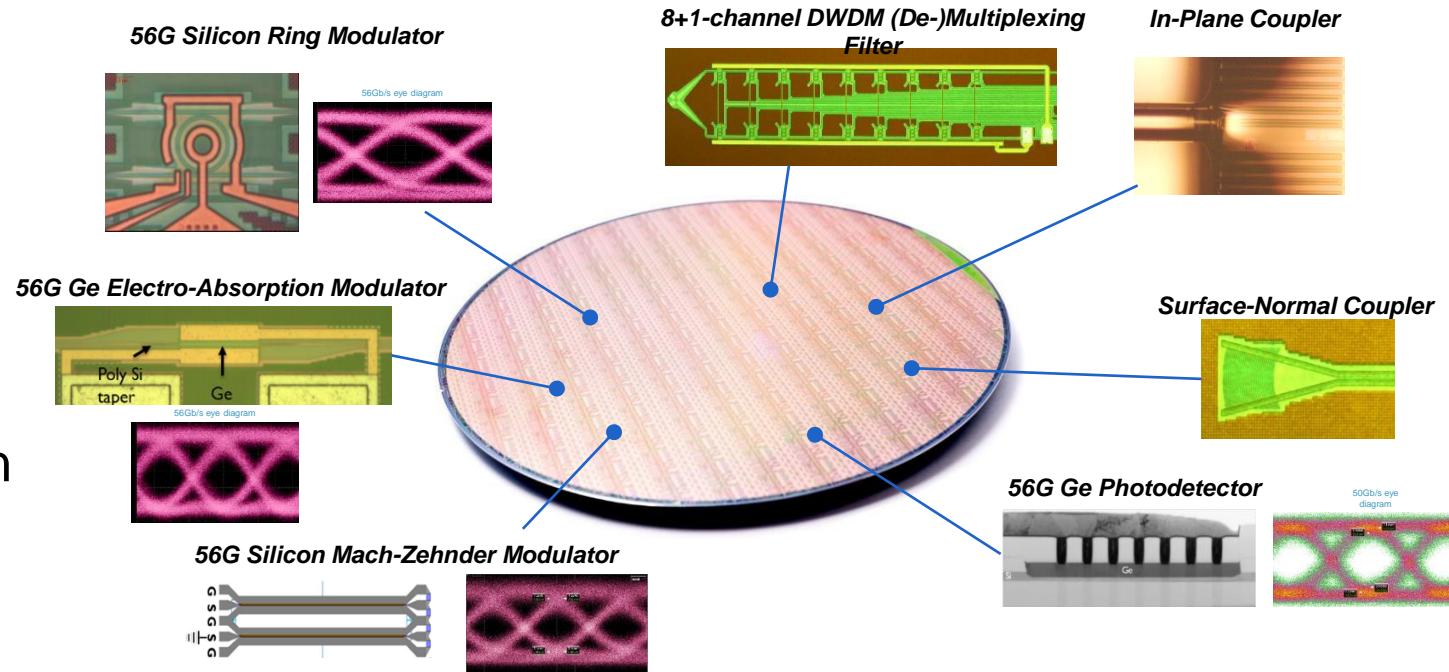
WHAT IS MISSING IN SI PHOTONICS?

IMEC's 56G platform

Missing



- III-V-on-Si integration
- SOAs on-chip
- Lasers on-chip

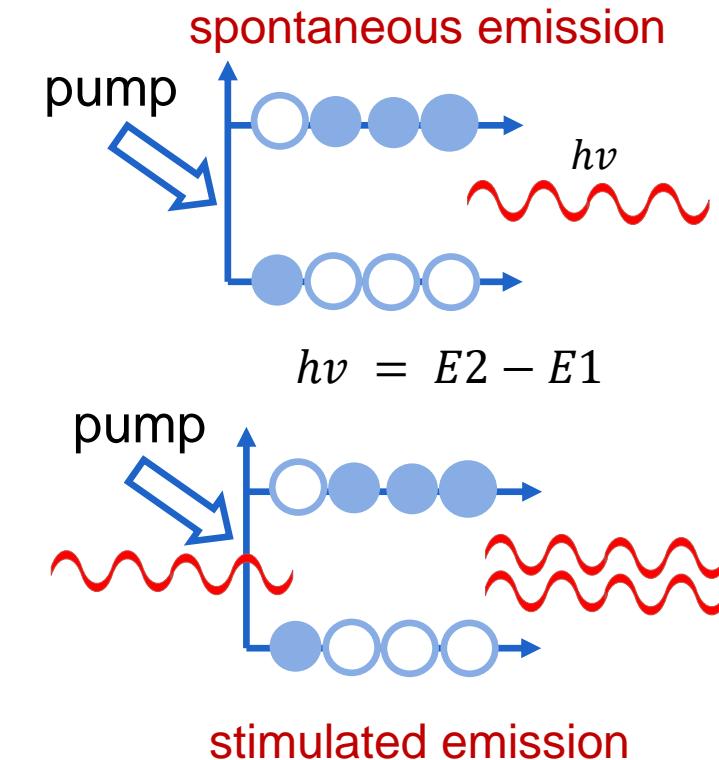
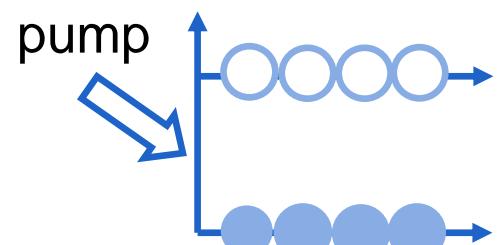
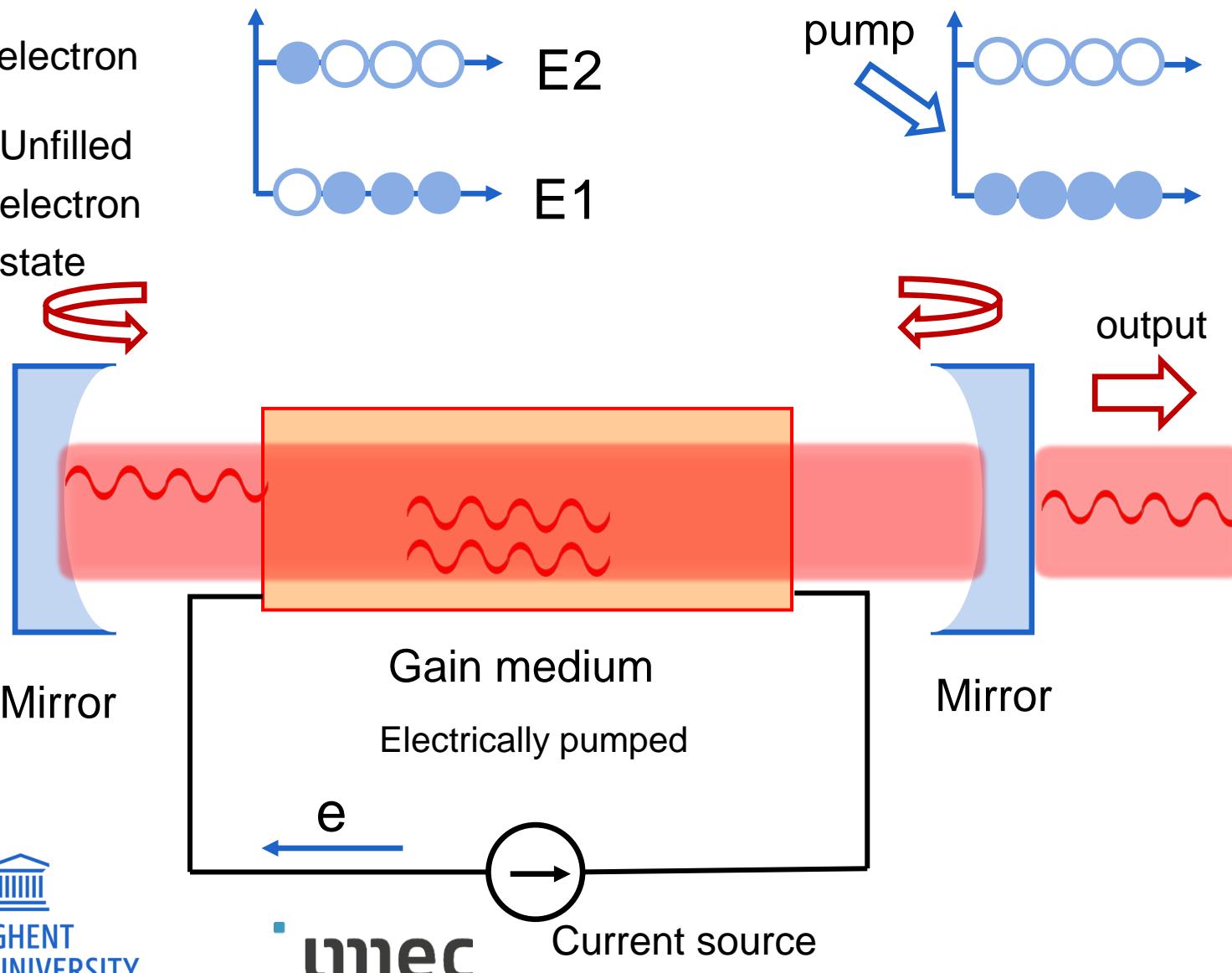


- Designed for 1.3 - 1.55 μm communication window
- Co-integration of the various building blocks in a single platform
- Today available on 200mm wafer size, coming soon on 300mm
- 95% compatible with CMOS130 in commercial foundries

WHAT IS A LASER?

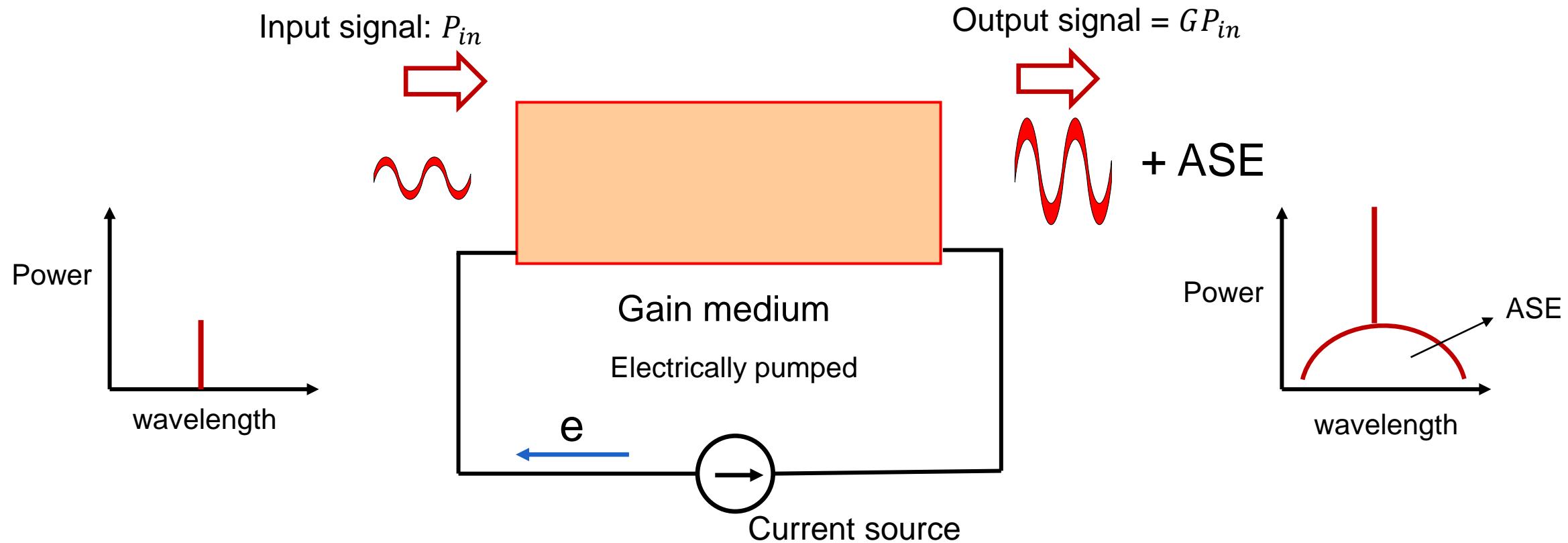
Light amplification by stimulated emission of radiation

- electron
- Unfilled electron state



WHAT IS A SOA?

Semiconductor optical amplifier



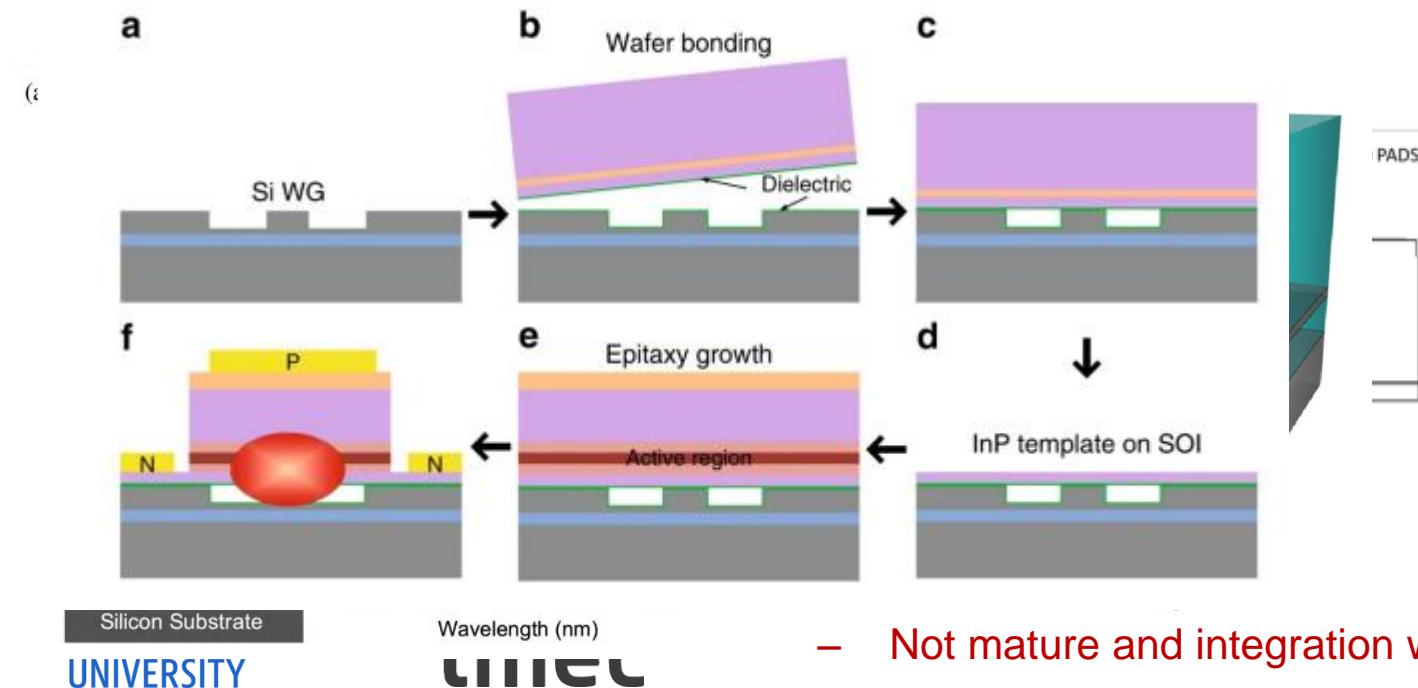
INTEGRATION OF III-V-ON-SILICON

Light sources/SOA

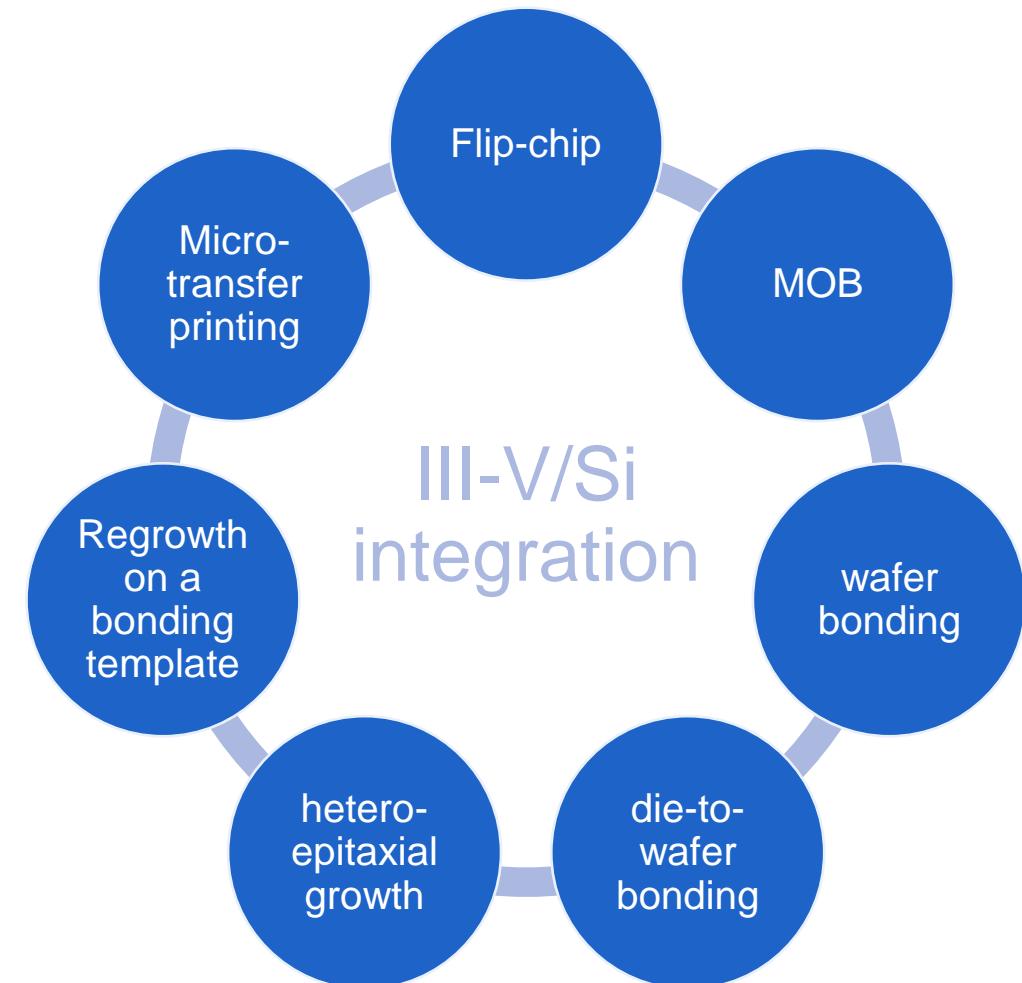


III-V direct bandgap materials

- Combines wafer bonding and epitaxial growth
- Enables growth of variety of III-V stacks in close proximity
- Lattice constant, interface polarity and expansion coefficients should be similar
- Growth thickness is limited to 450 nm

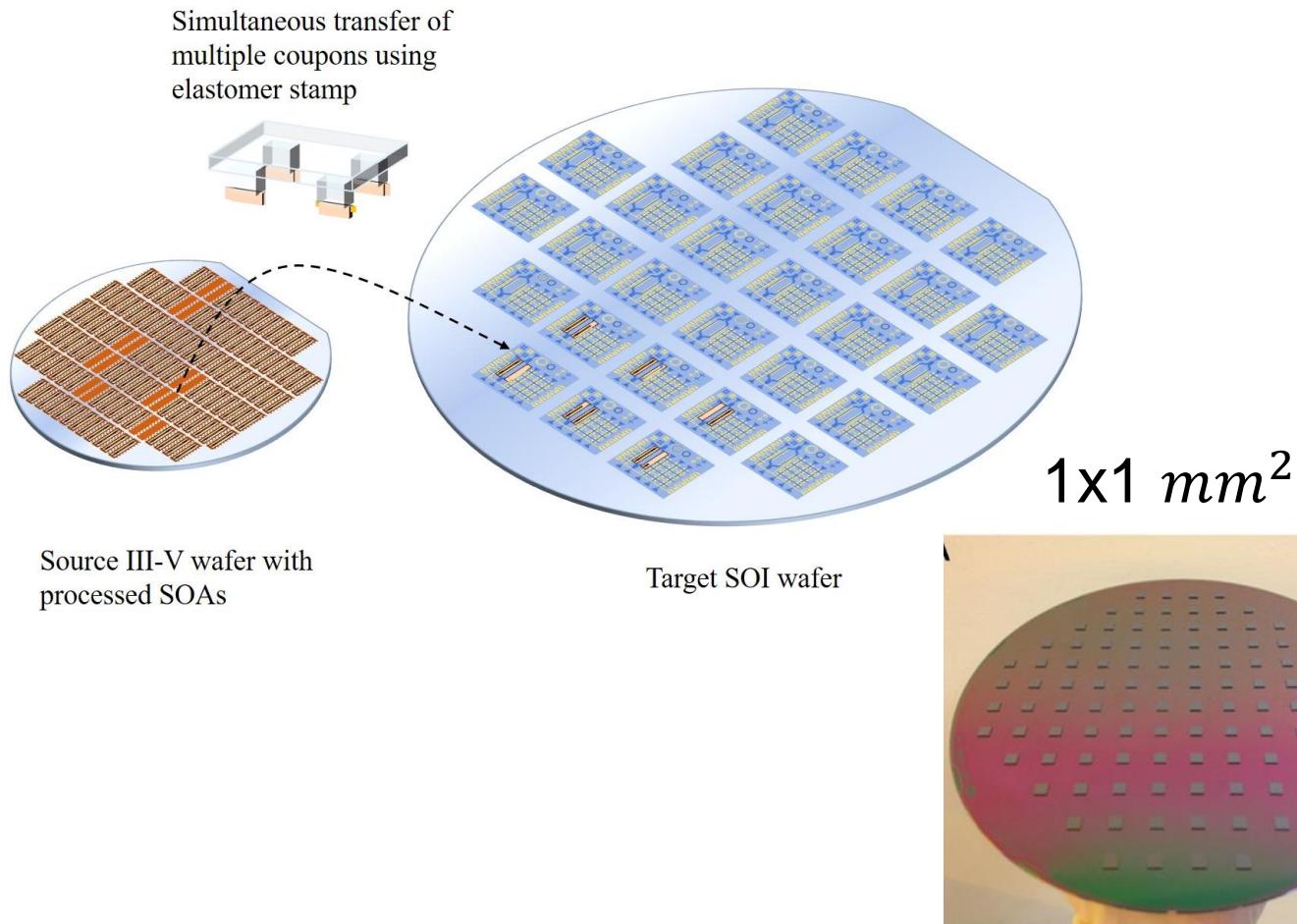


Existing technologies



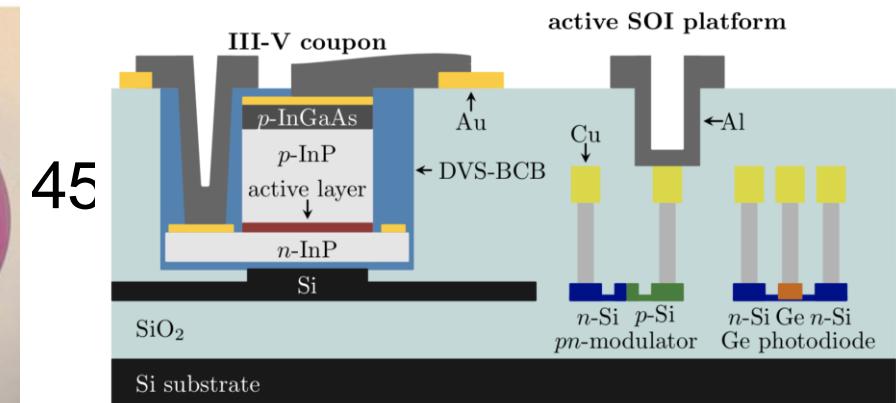
- Not mature and integration with a full SiPh process flow is challenging

MICRO-TRANSFER PRINTING-CONCEPT



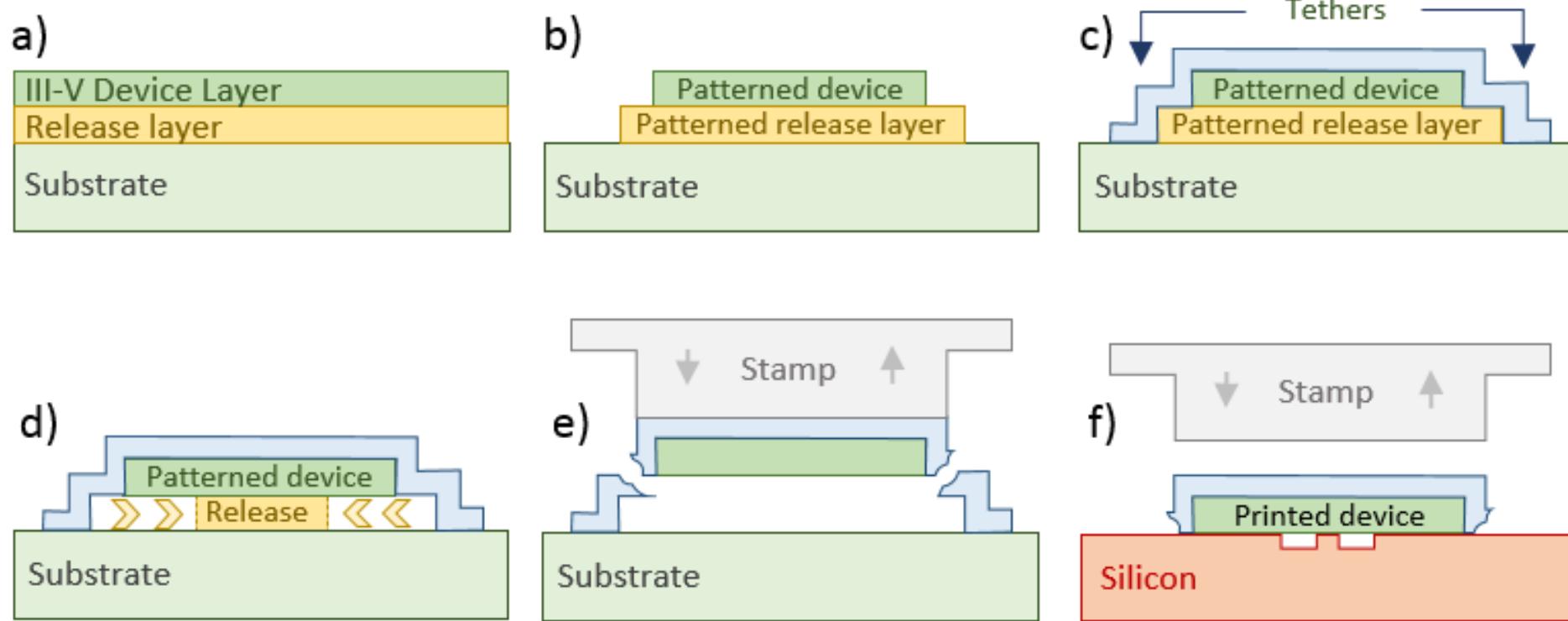
Advantages:

- Efficient use of expensive III-V material/devices
- Devices with different layer epitaxial structure can be populated closely on the SOI wafer.
- Integration of the devices doesn't require modification of FEOL and BEOL Si photonics process in a commercial foundry (modular).



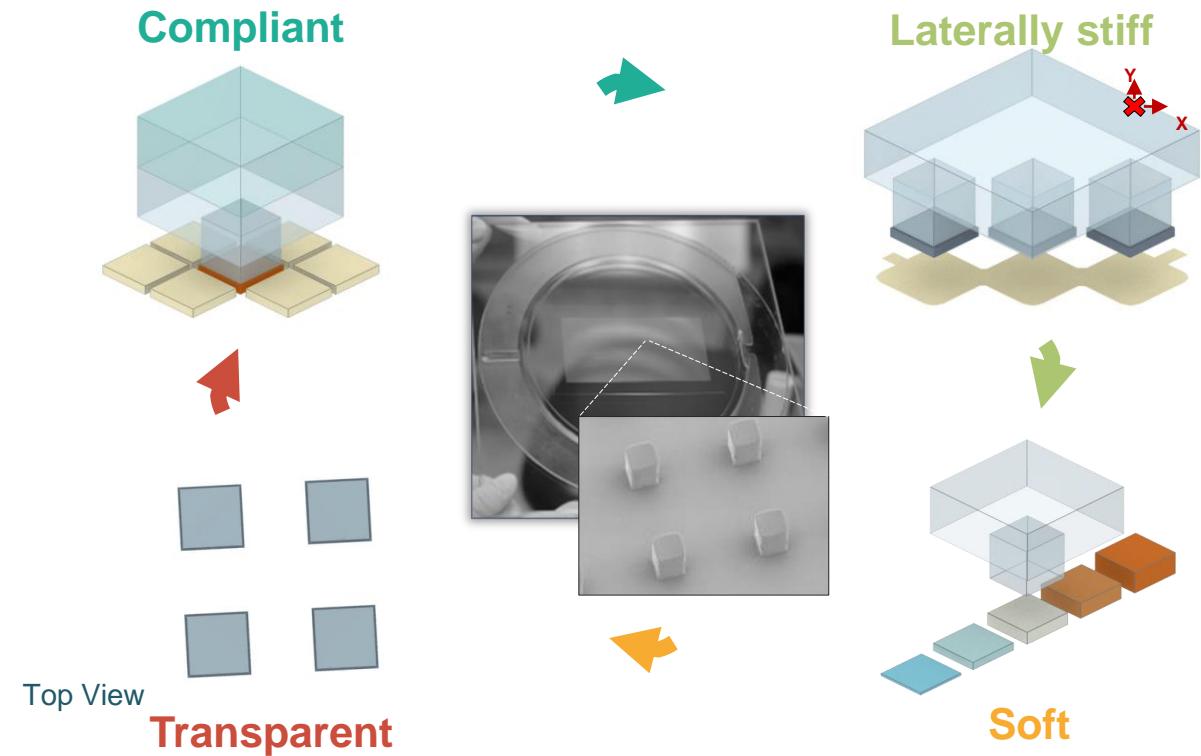
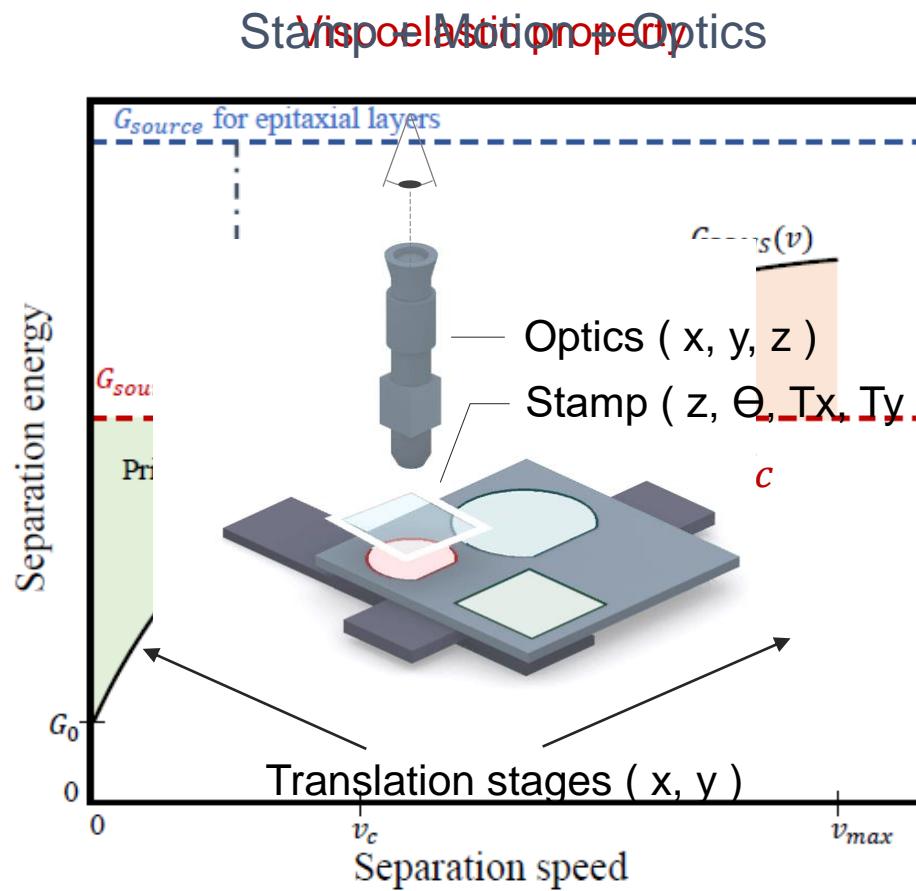
Combines wafer bonding integration approach with flip-chip

PROCESS FLOW OF μ TP

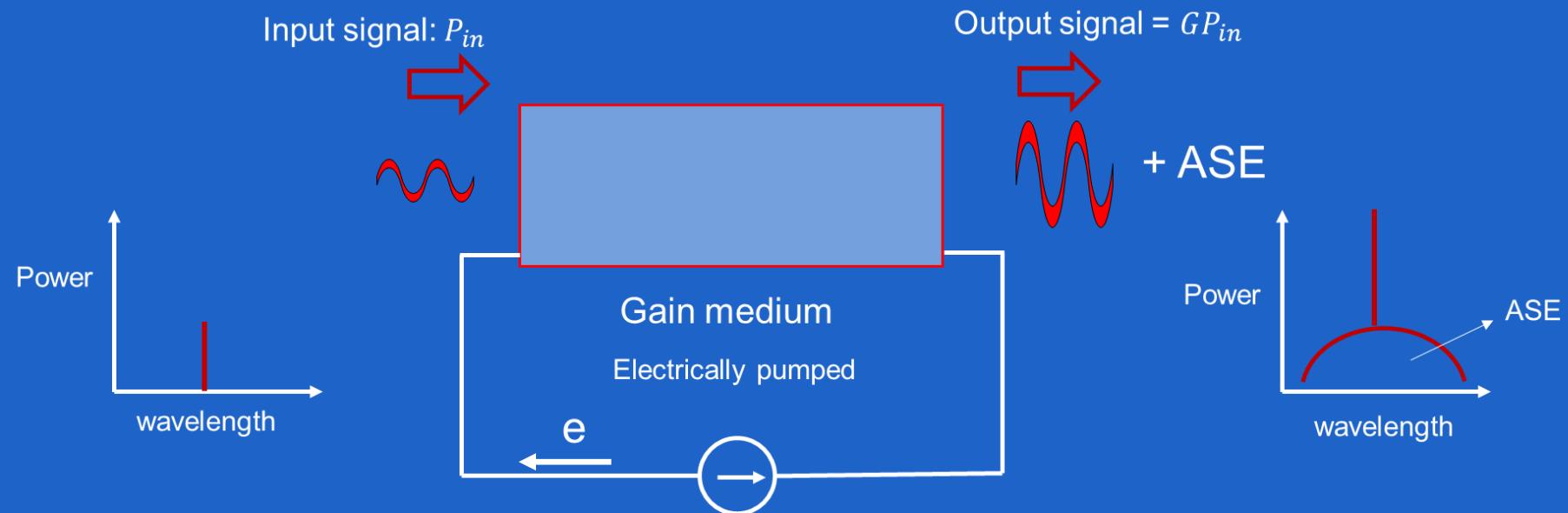


Release layer is incorporated underneath the device functional layers

PROPERTIES OF PDMS STAMPS

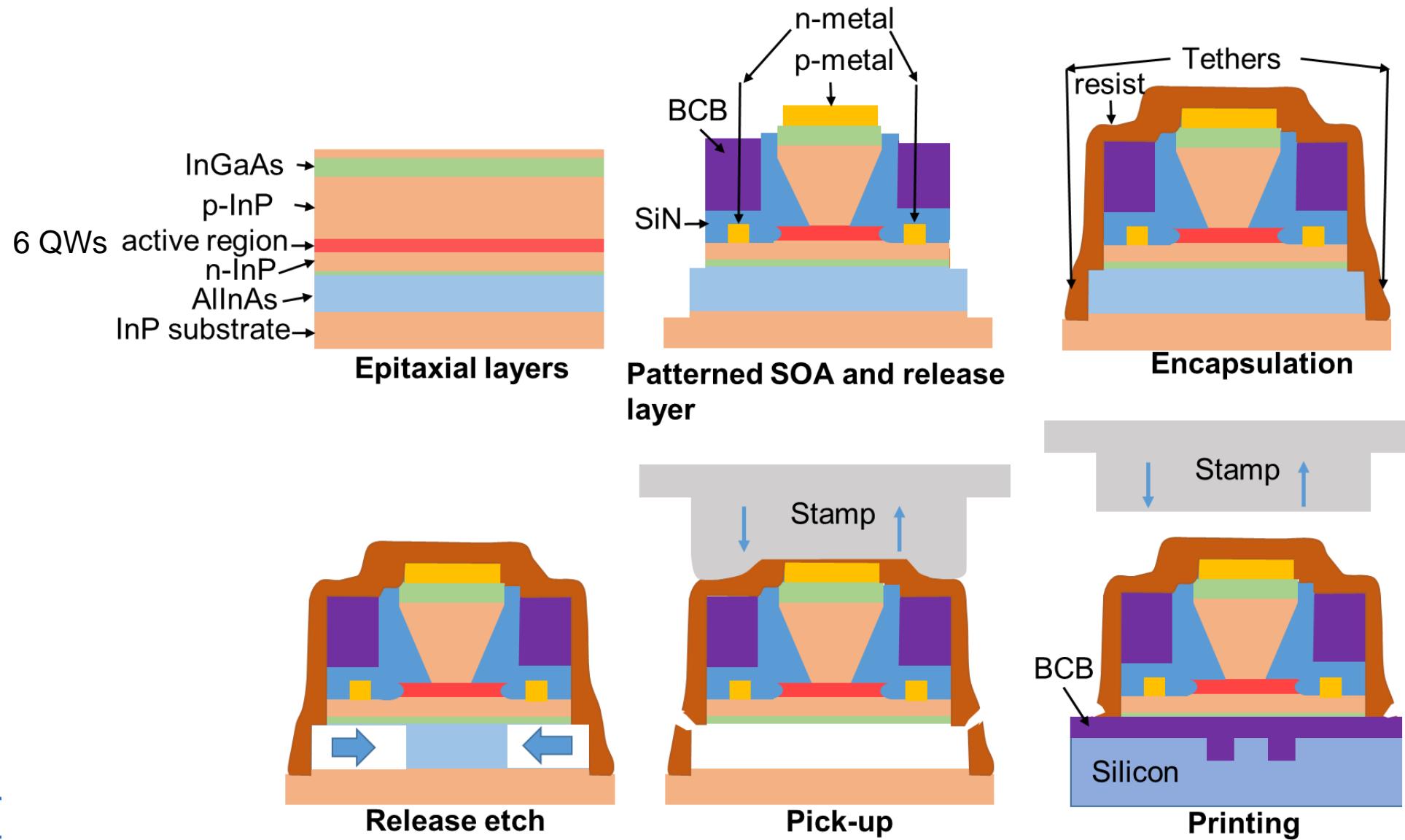


μ TP is enabled by PDMS stamps

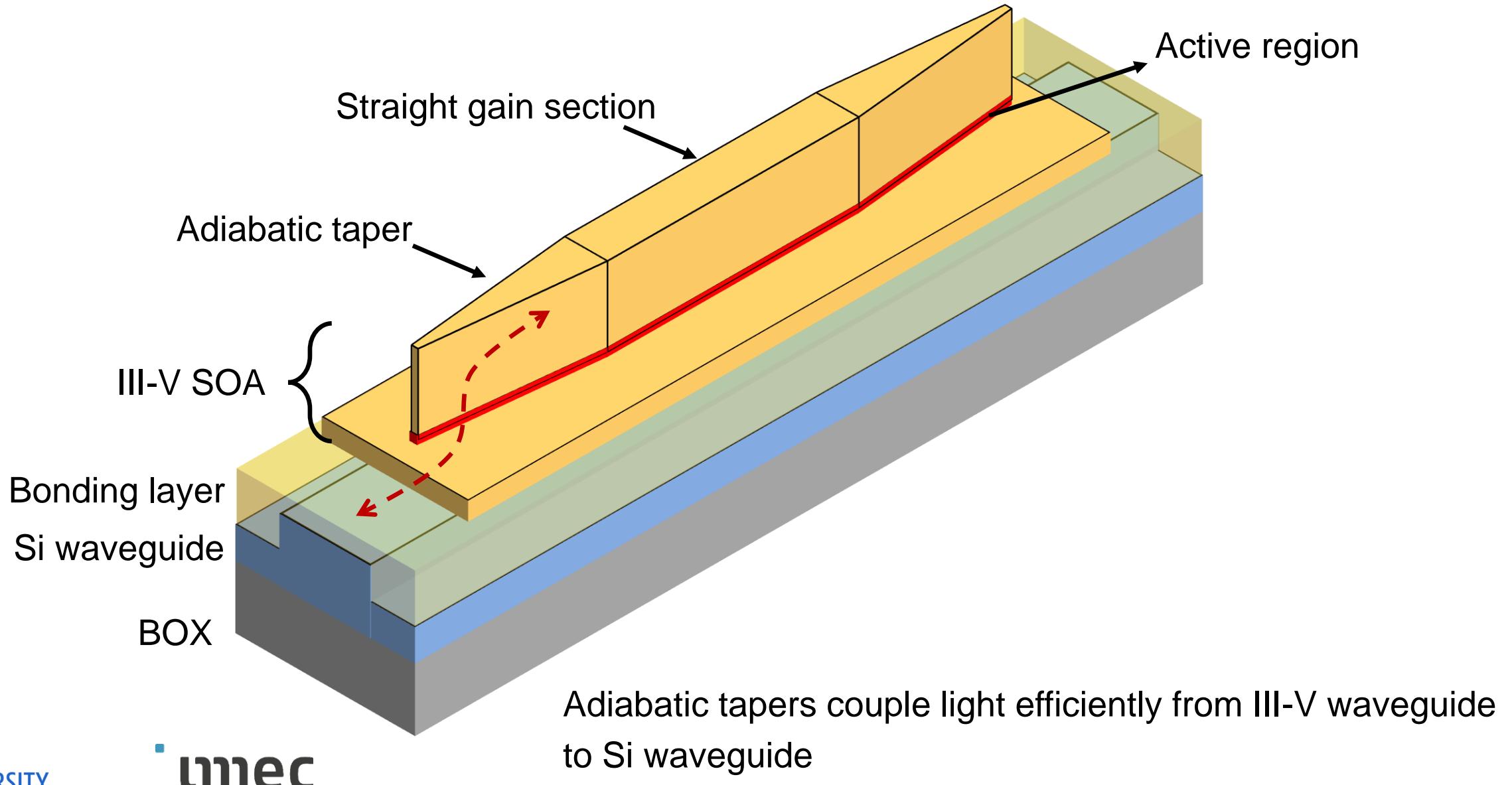


μ TRANSFER-PRINTED III-V-ON-SI SOA

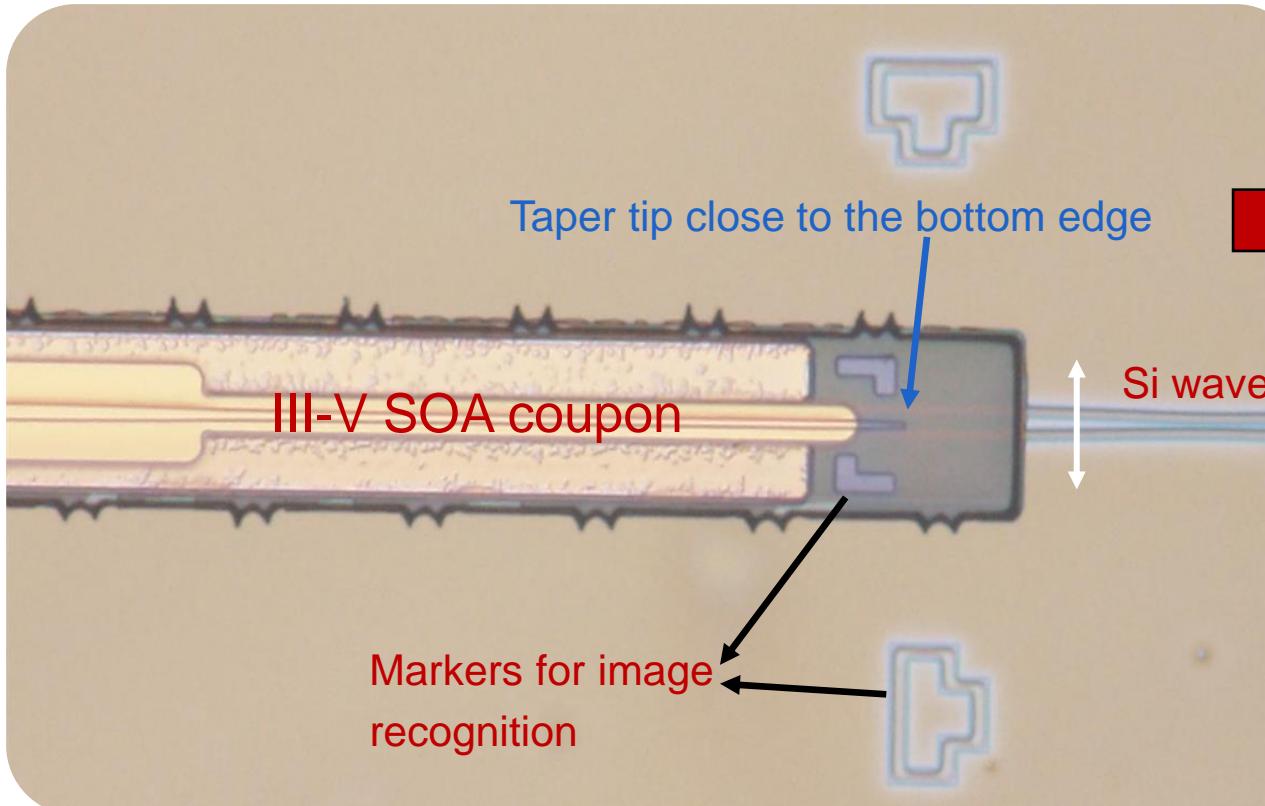
MICRO-TRANSFER-PRINTING SOA PROCESS FLOW



STRUCTURE OF A III-V-ON-SI SOA

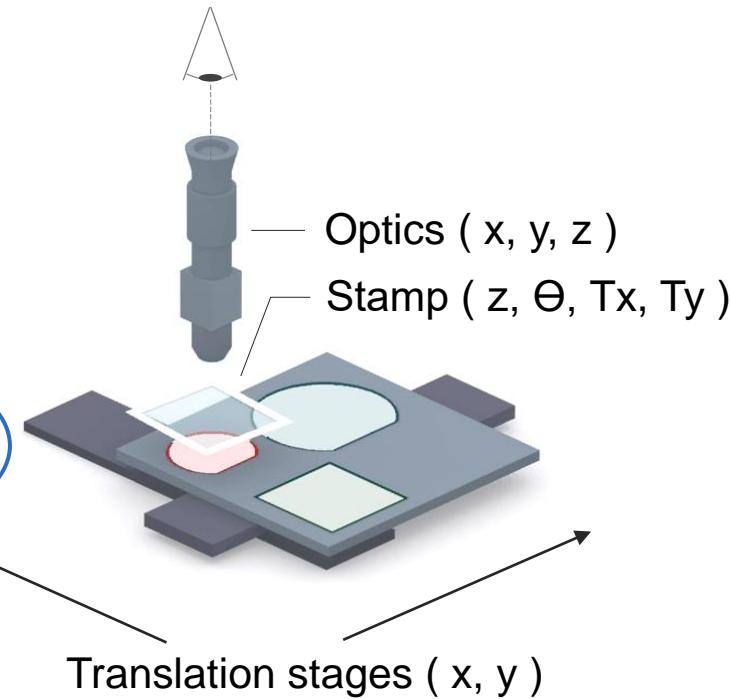


BANE OF TP PRE-PROCESSED SOAS



Challenge

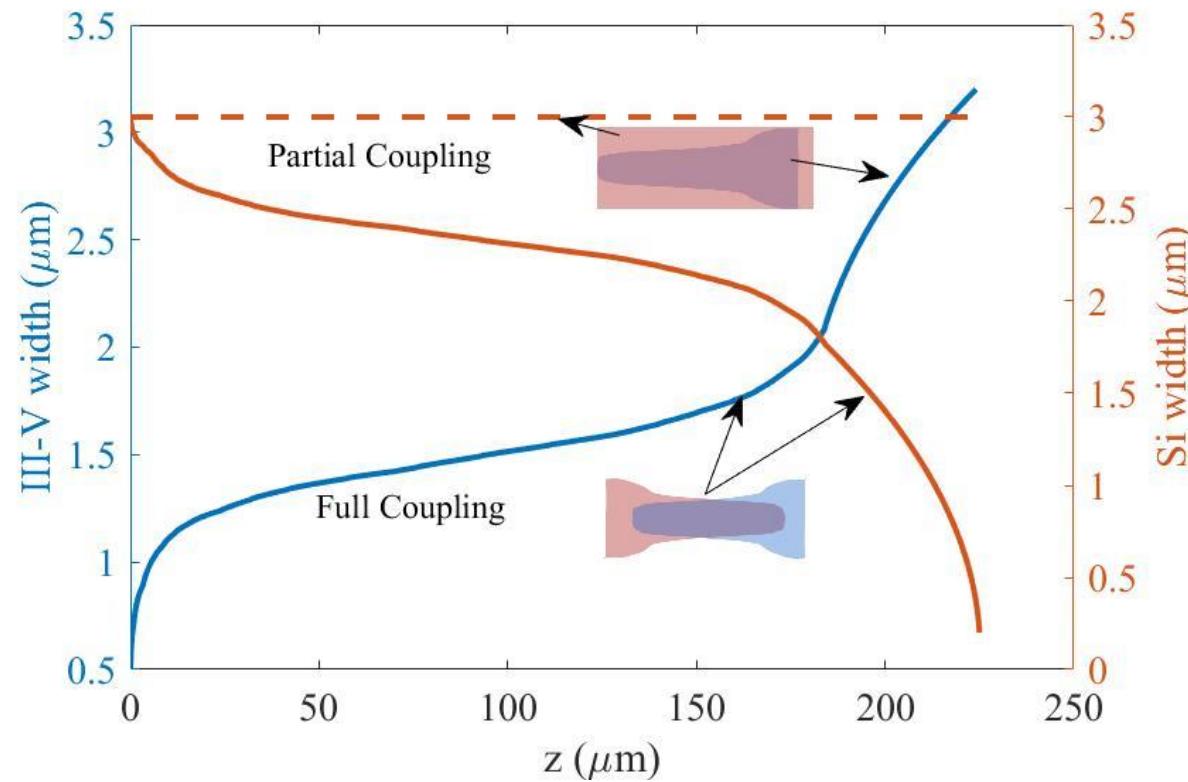
Alignment-tolerant
coupling taper



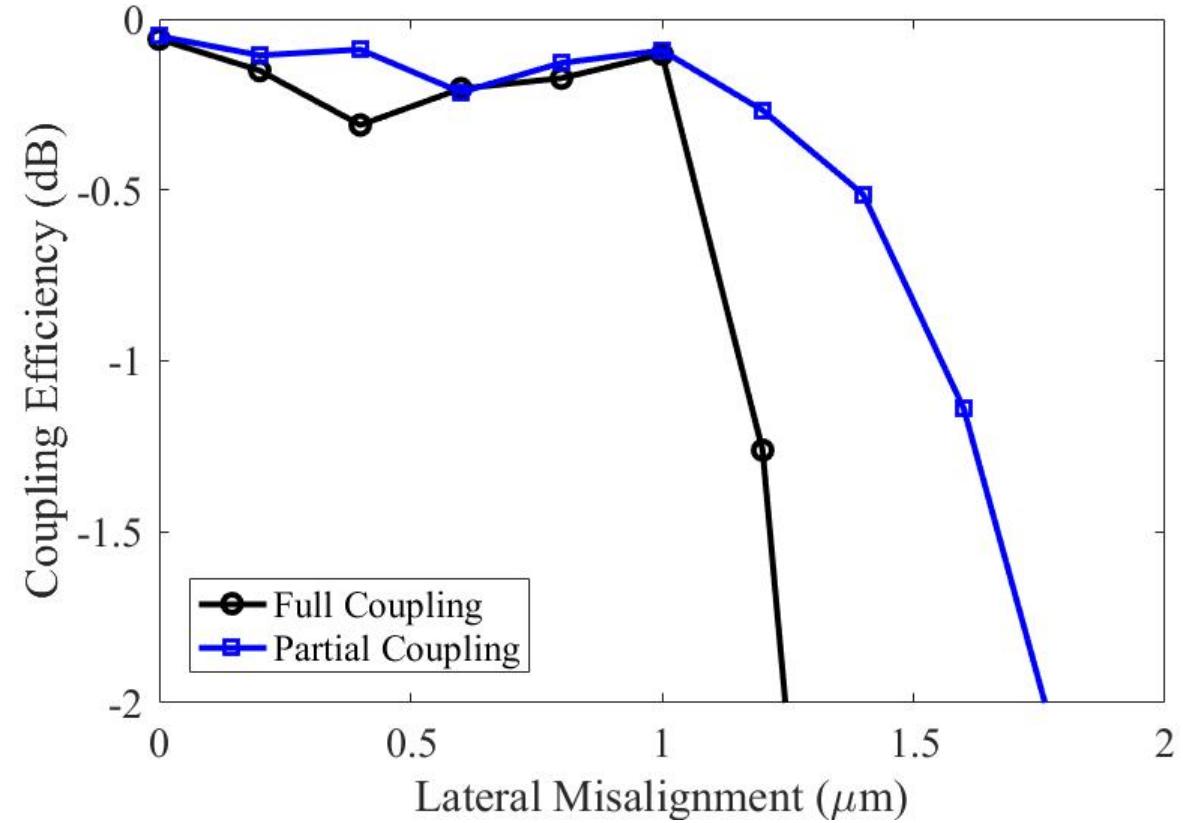
State of the art transfer printing tools provides an alignment accuracy of $\pm 1.5 \mu\text{m} 3\sigma$

MICRO-TP COMPATIBLE ADIABATIC TAPER

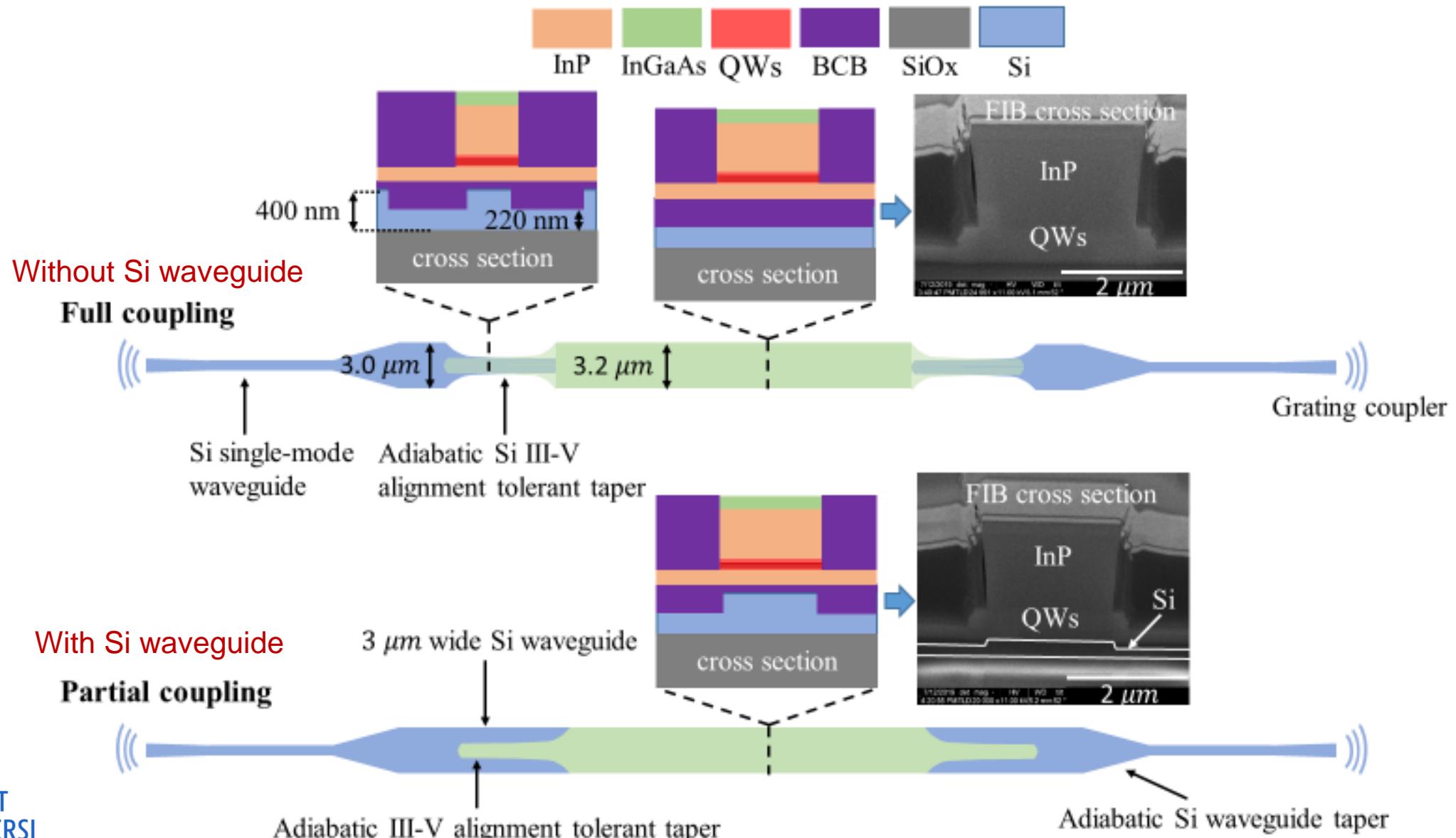
Shape of the adiabatic taper



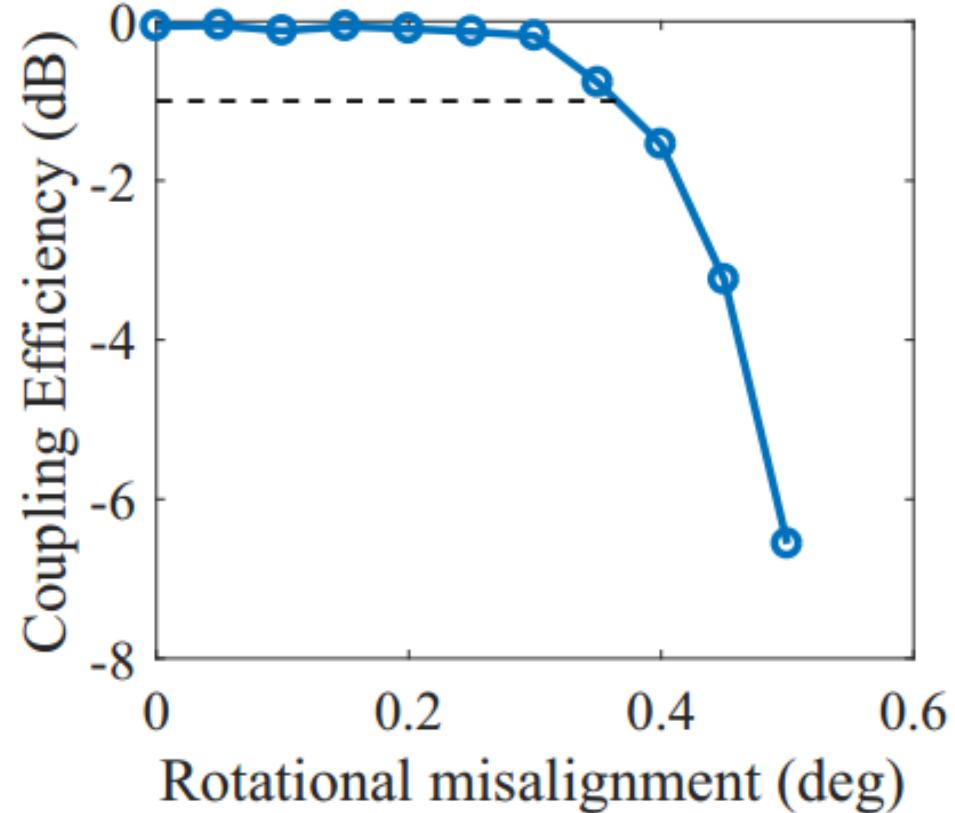
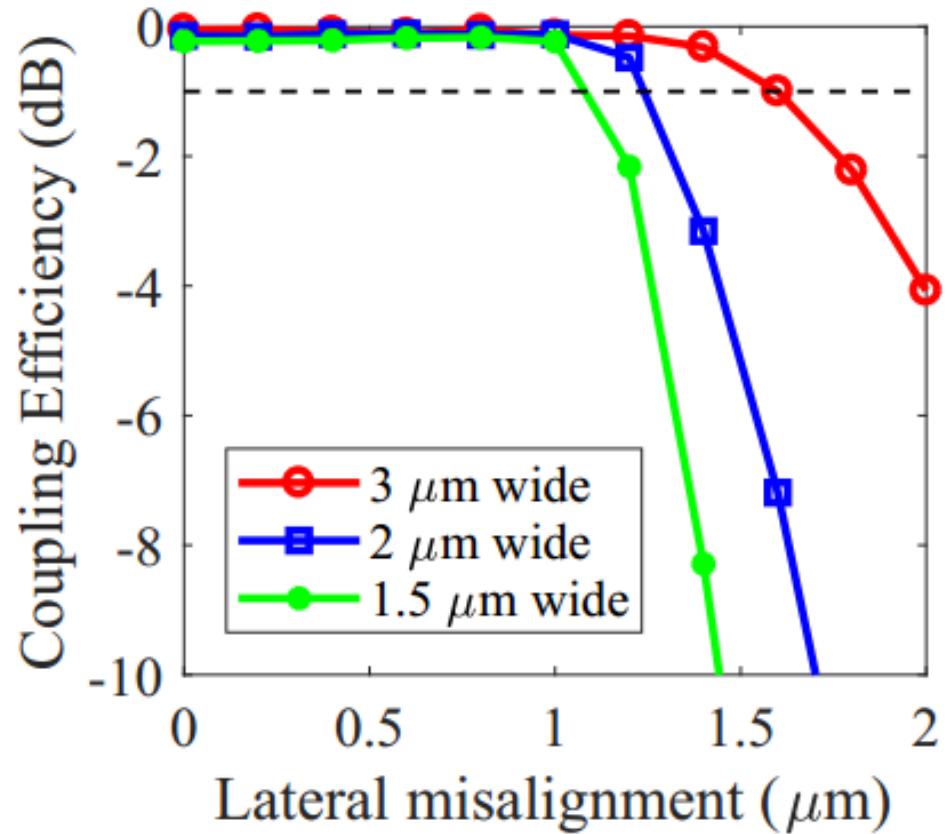
Calculated coupling efficiency with misalignment



DESIGN OF III-V-ON-SILICON SOA

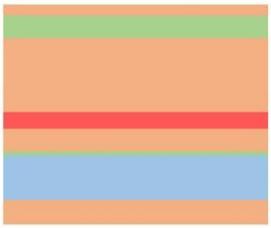


FULL COUPLING DESIGN WORKS IN BOTH CASES

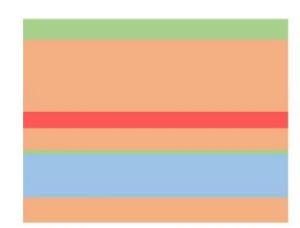


Full coupling adiabatic taper design also shows high power coupling to Si waveguides of various widths.

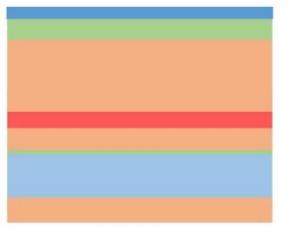
PROCESSING ON THE INP SOURCE



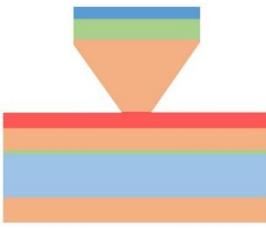
a) Epitaxial layer



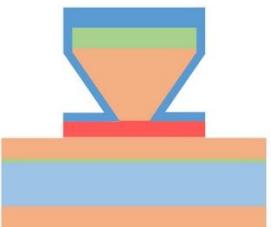
b) Sacrificial layer removal



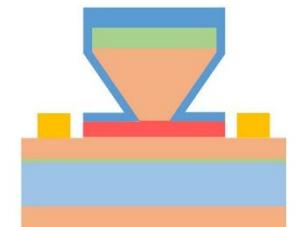
c) PECVD SiNx deposition



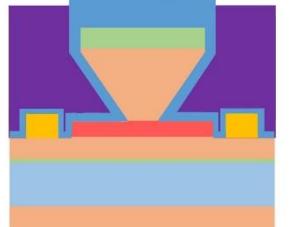
d) SOA mesa etching



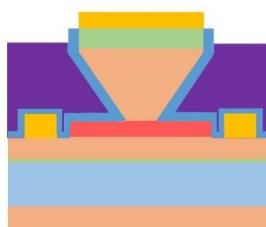
e) QW patterning



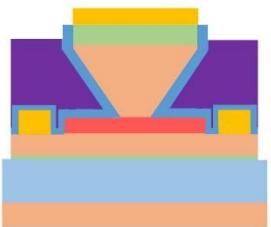
f) n-metal deposition



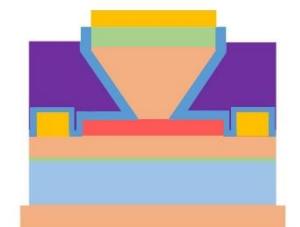
g) SiNx and BCB



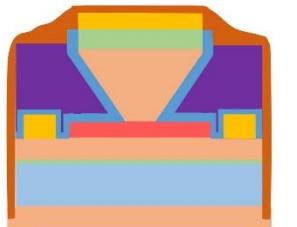
h) p-metal deposition



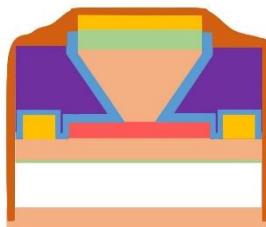
i) BCB etch-back



j) Release layer etch

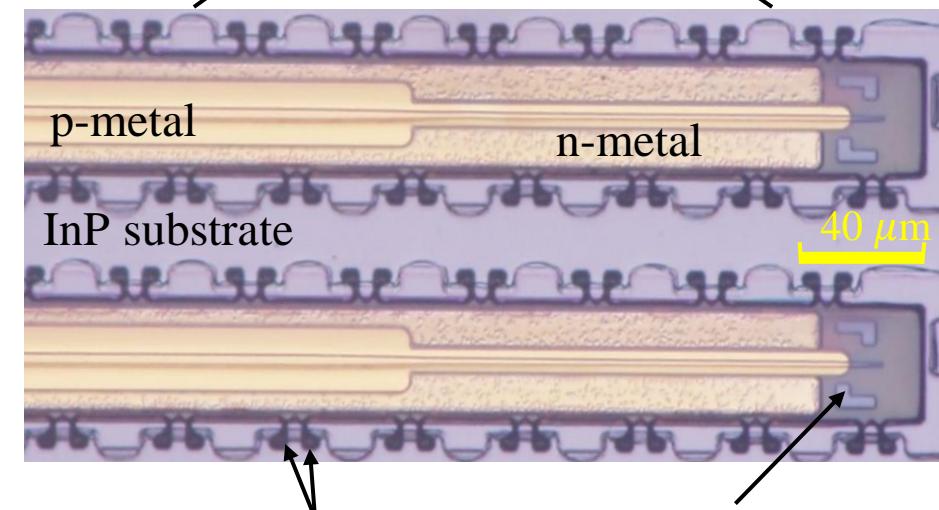
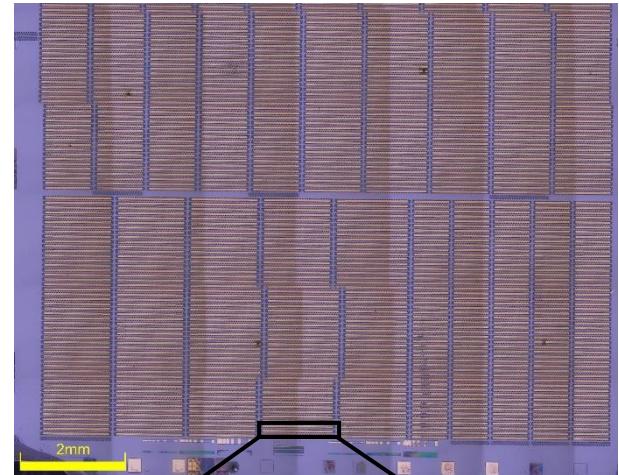


k) Encapsulation



l) Released SOA coupon

Processed in dense arrays



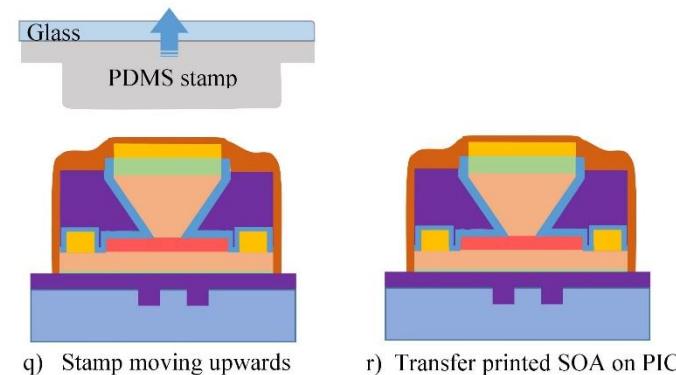
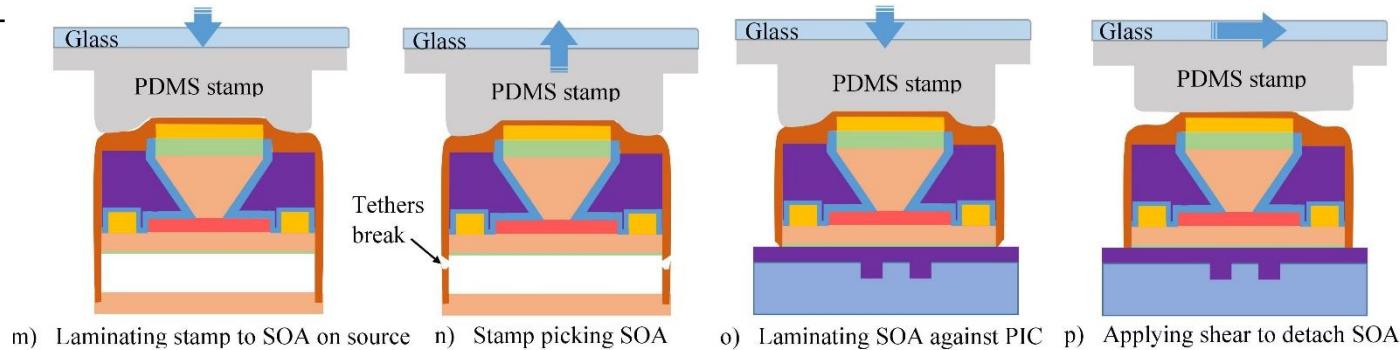
Standard i-line contact lithography



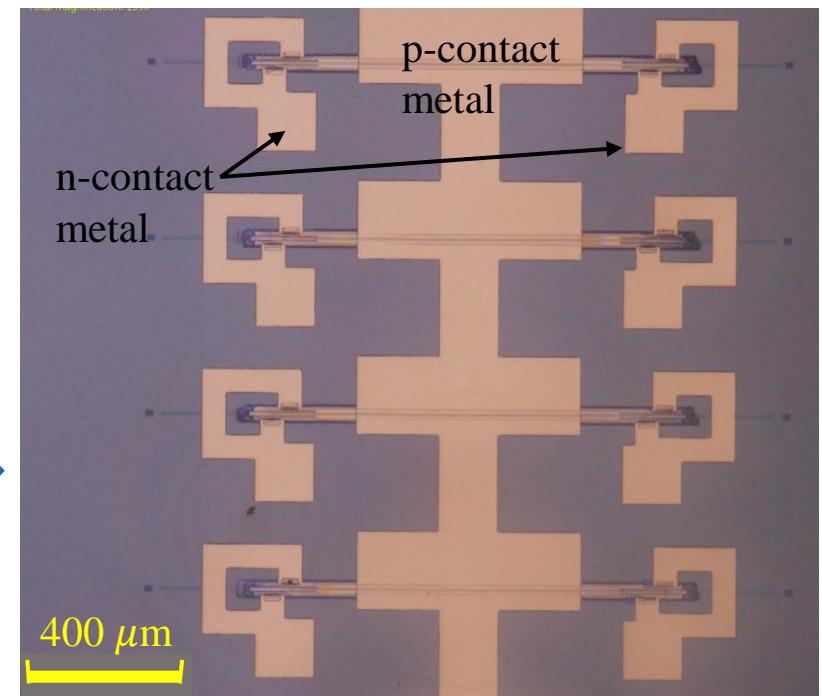
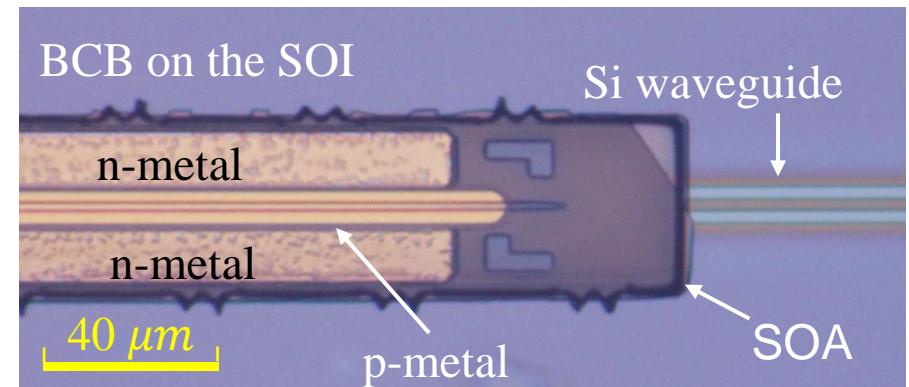
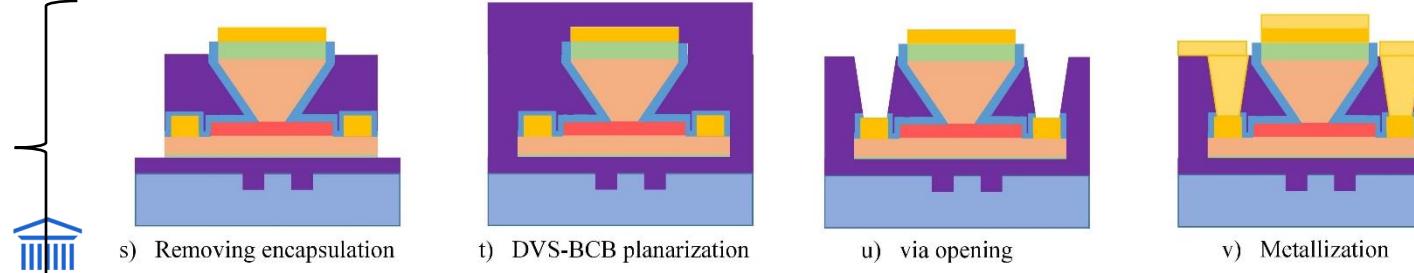
TRANSFER PRINTING AND POST PROCESSING

After printing on the SOI

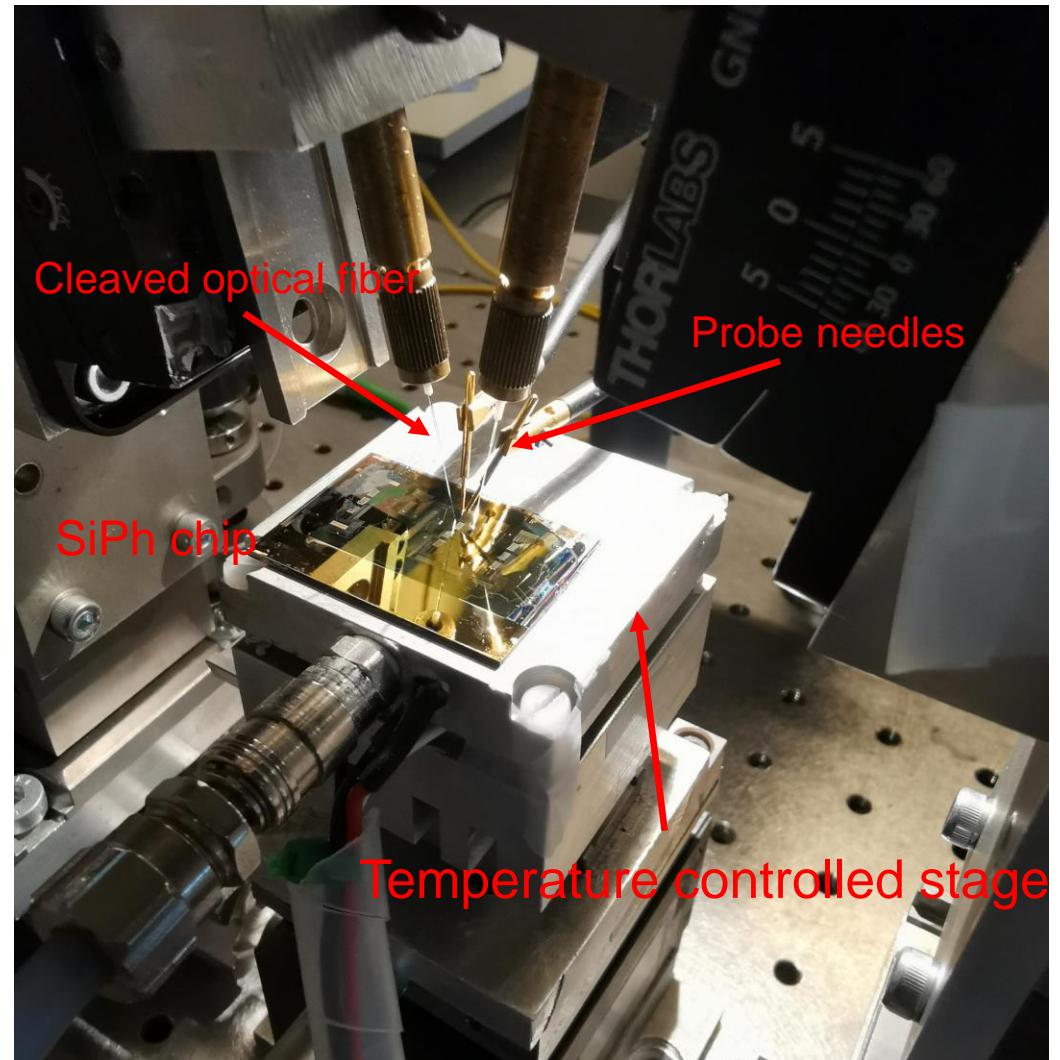
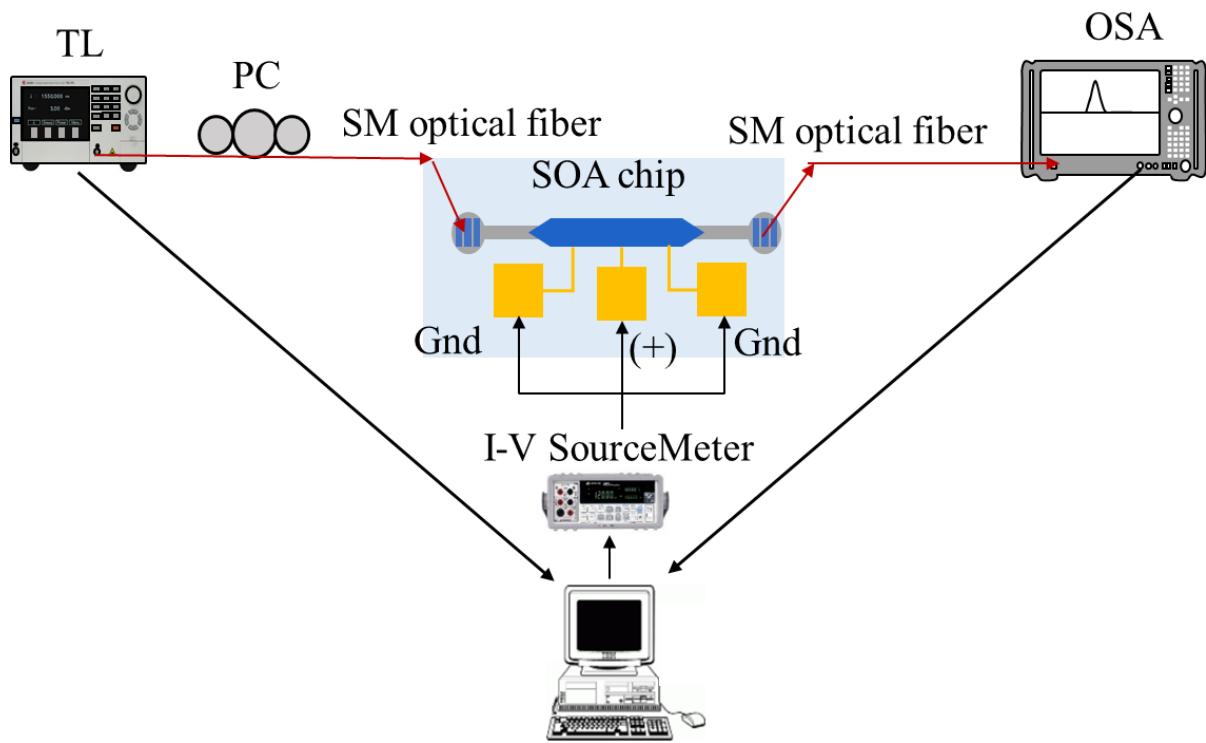
Transfer printing



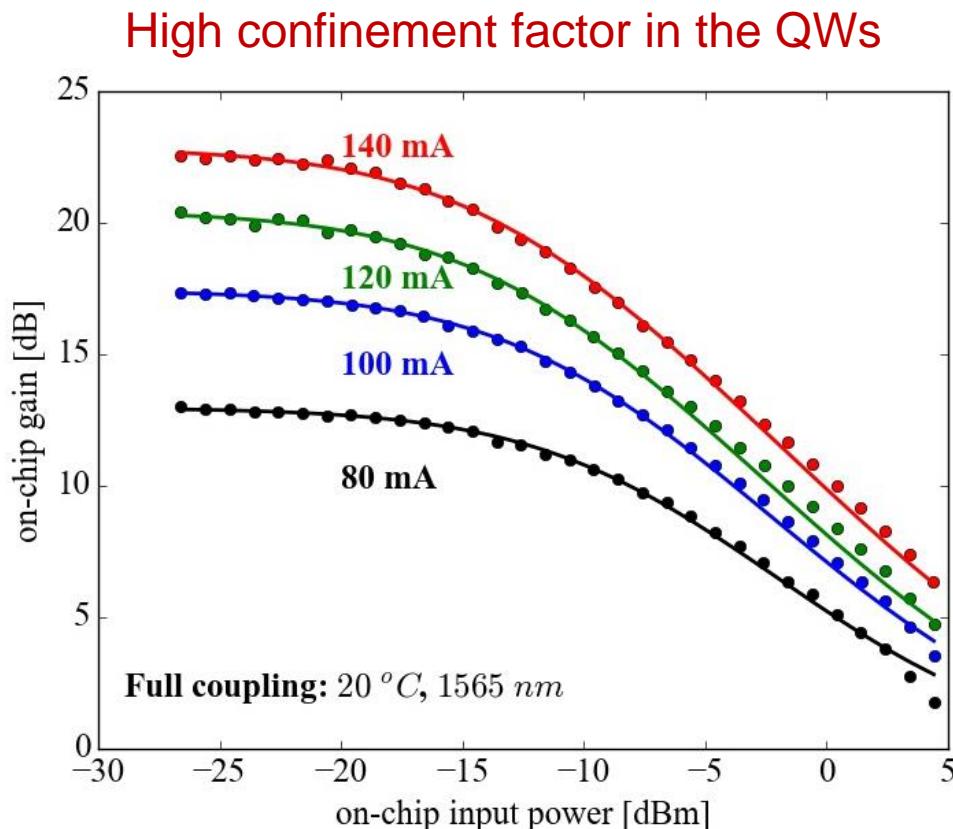
Post processing
on the SOI



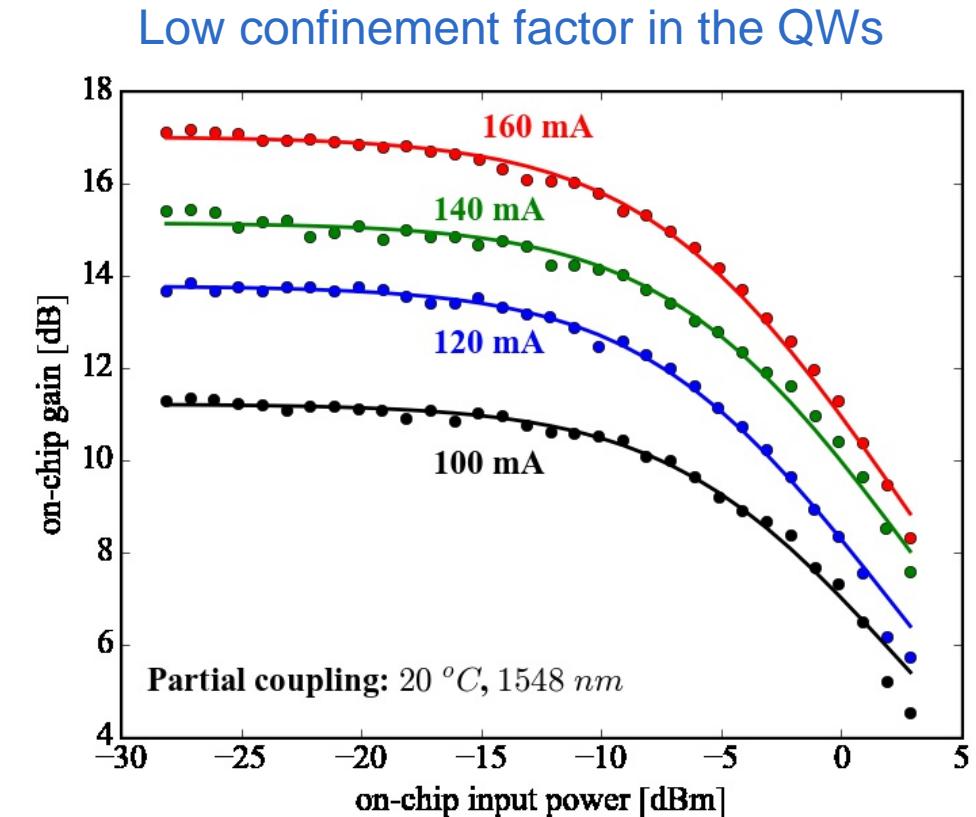
MEASUREMENT SETUP



ON-CHIP GAIN AND POWER SATURATION

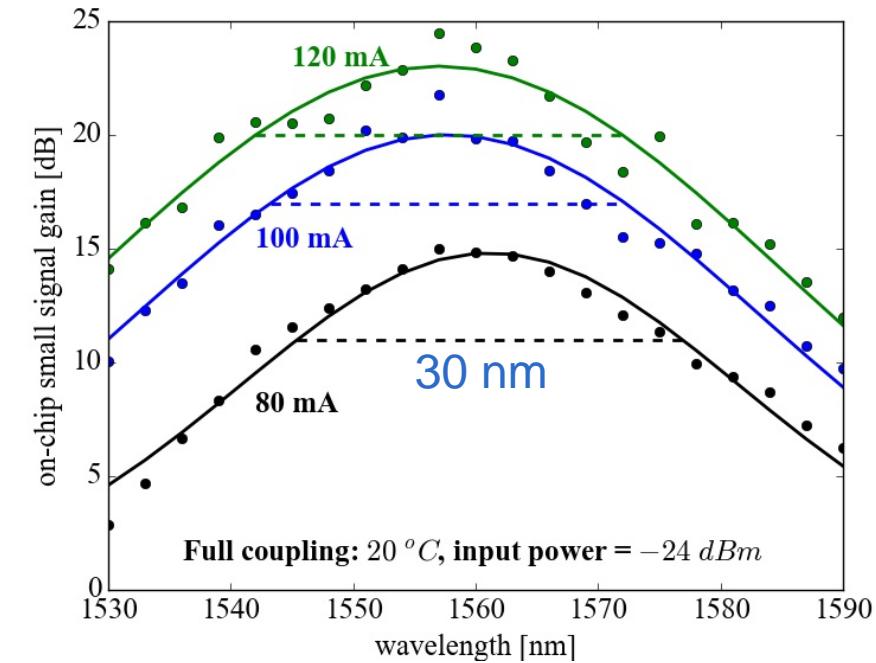
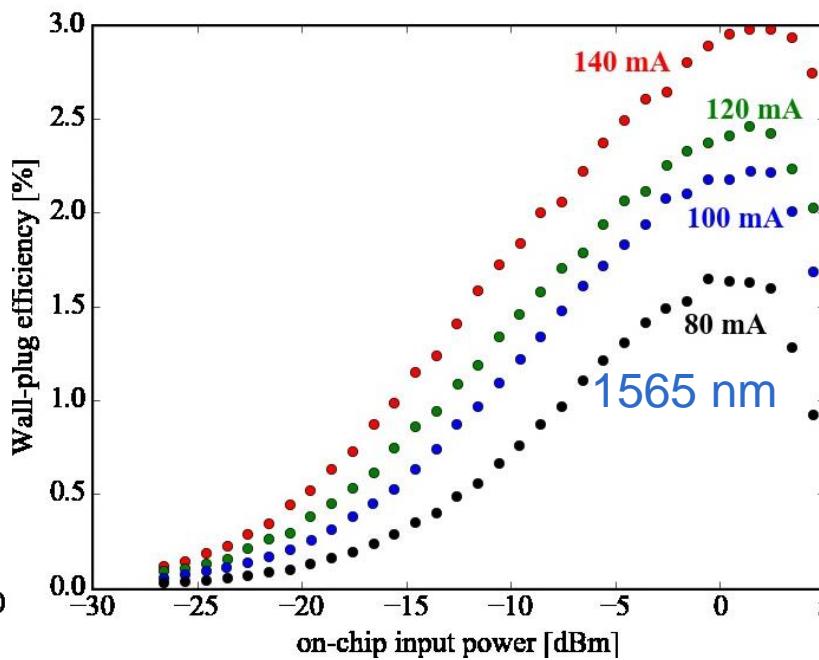
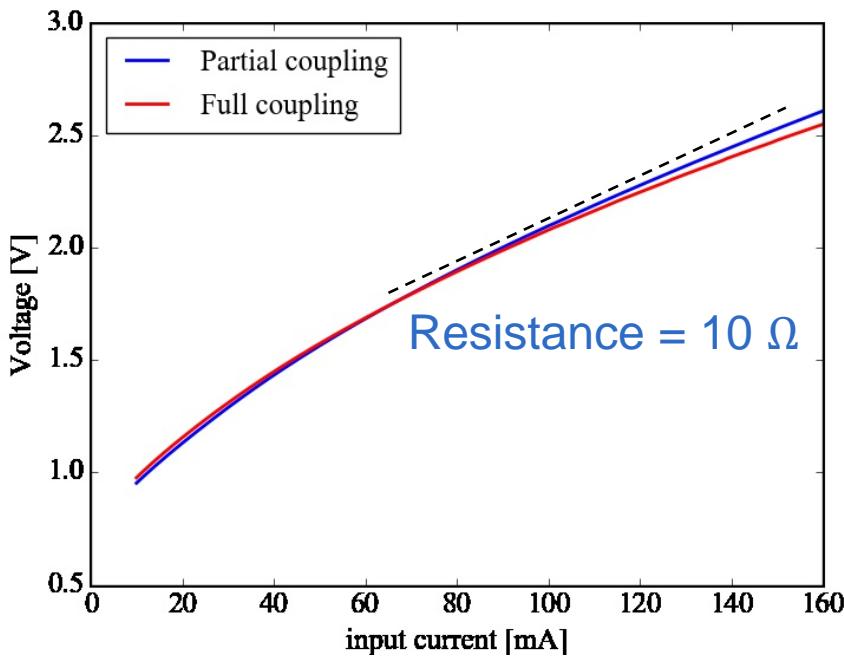


At 140 mA, the measured on-chip small signal gain is 23 dB and output power saturation is 9 mW.



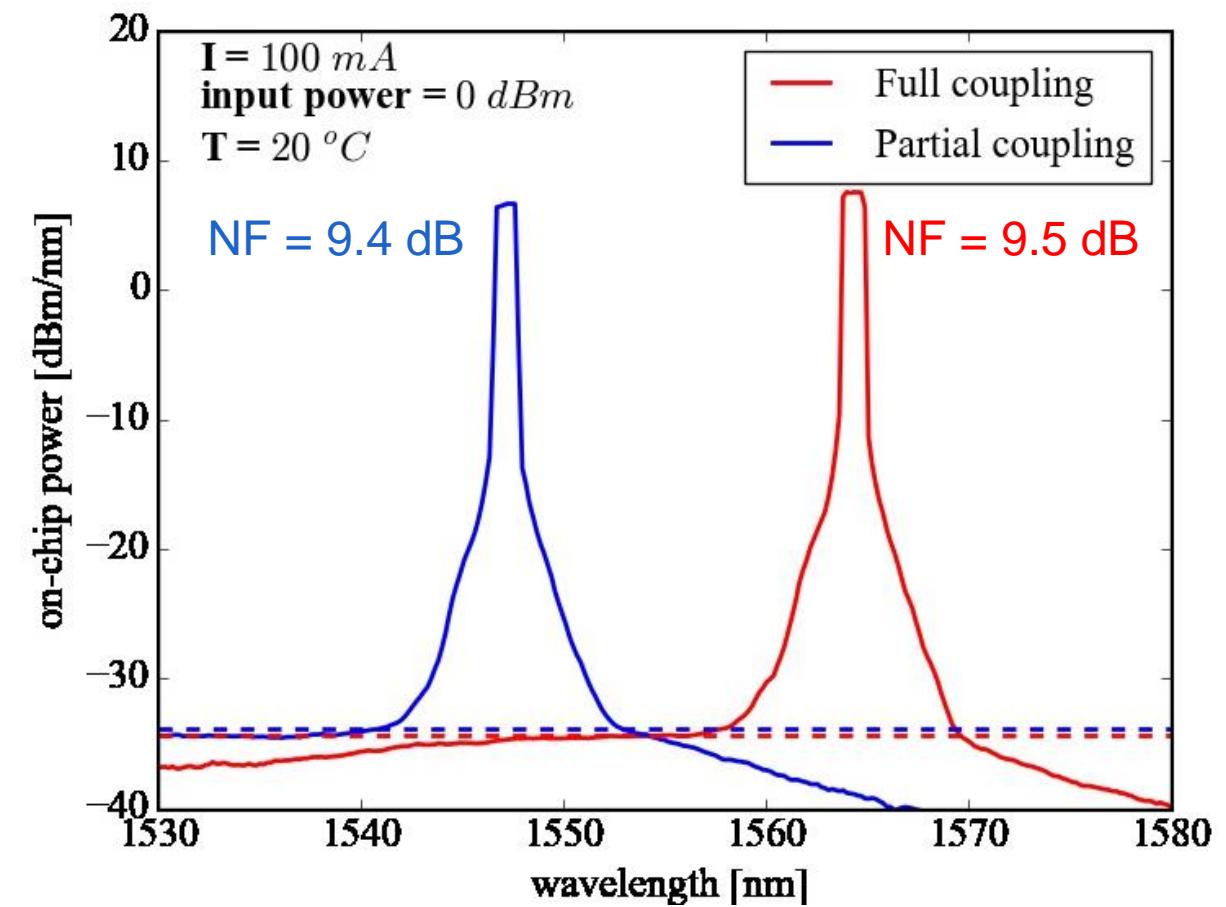
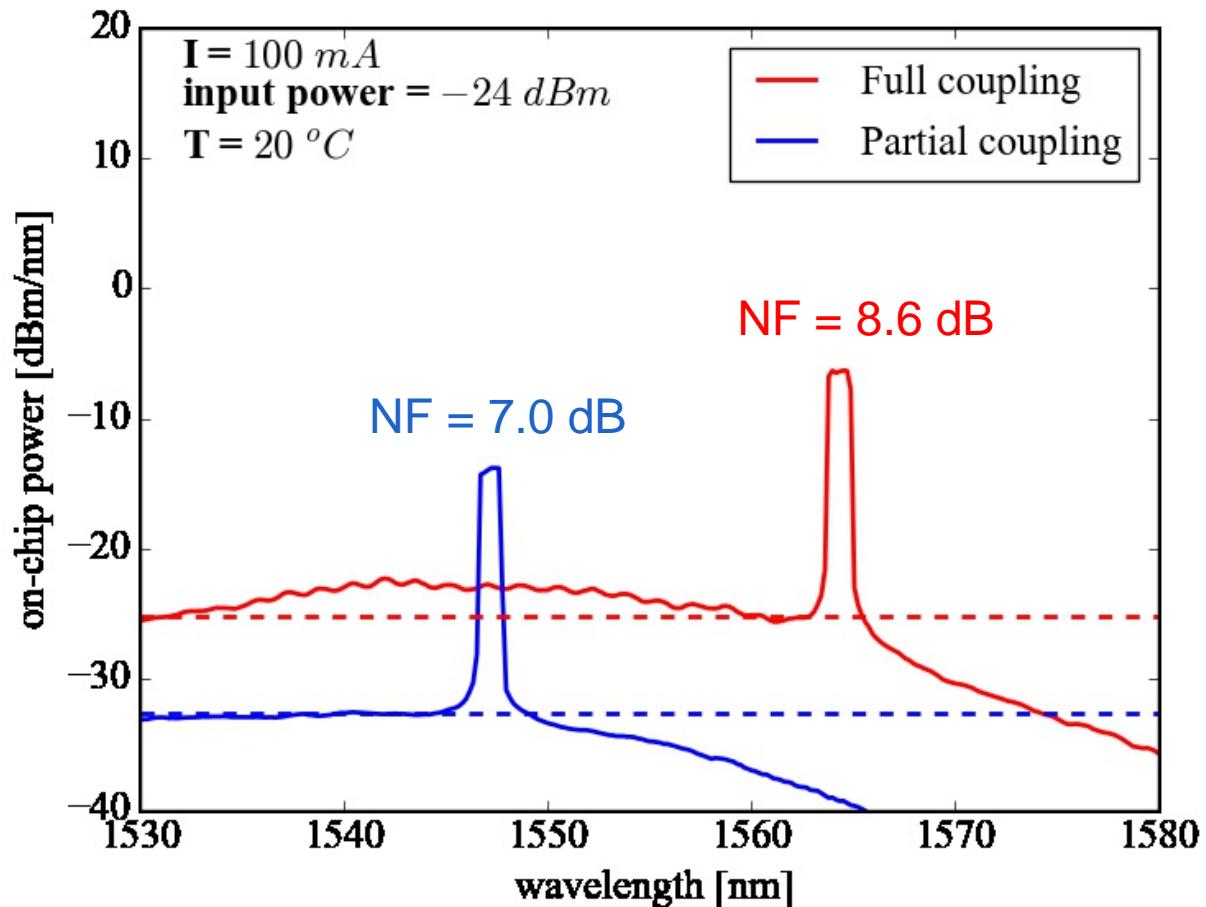
At 160 mA, the measured on-chip small signal gain is 17 dB and output power saturation is 17 mW.

BANDWIDTH AND WALL-PLUG EFFICIENCY



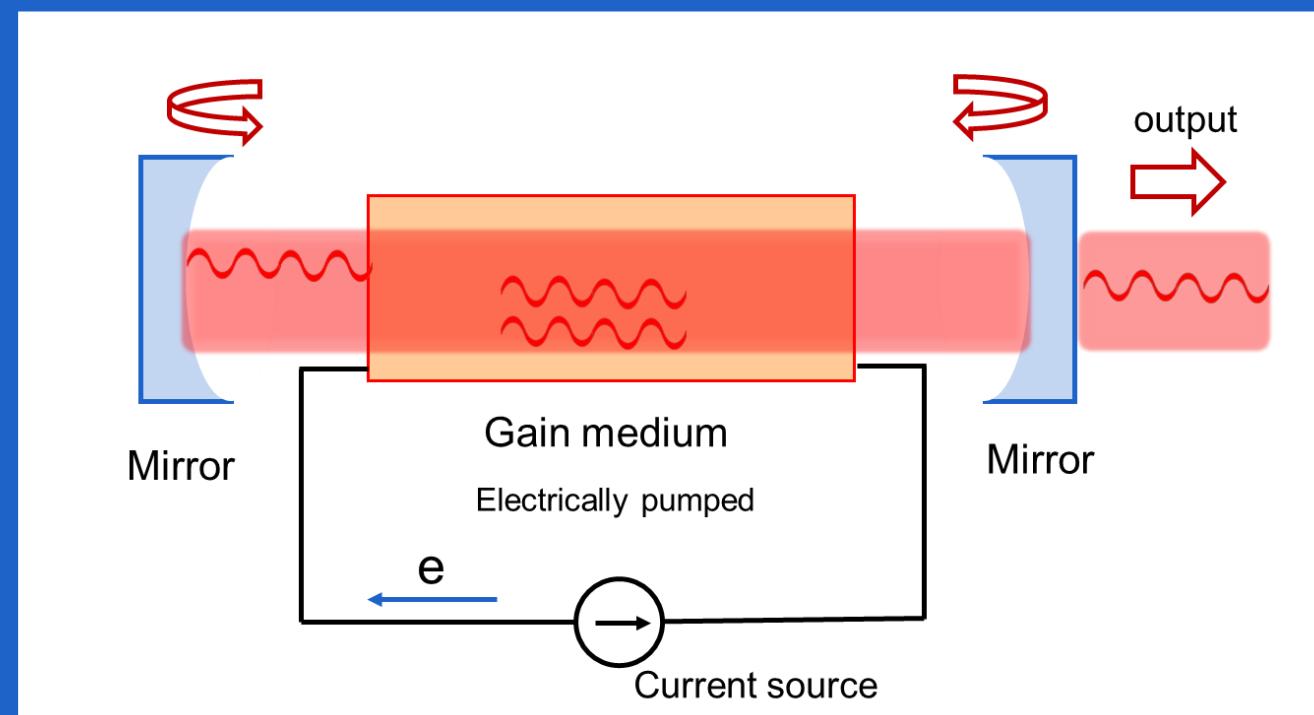
Both the amplifiers have similar 3-dB bandwidth, maximum Wall-plug efficiency and resistance.

NOISE FIGURE



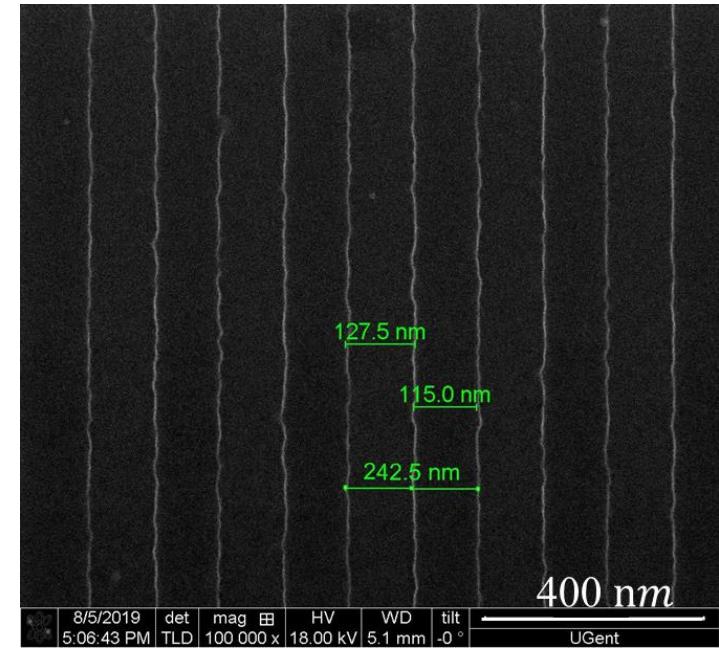
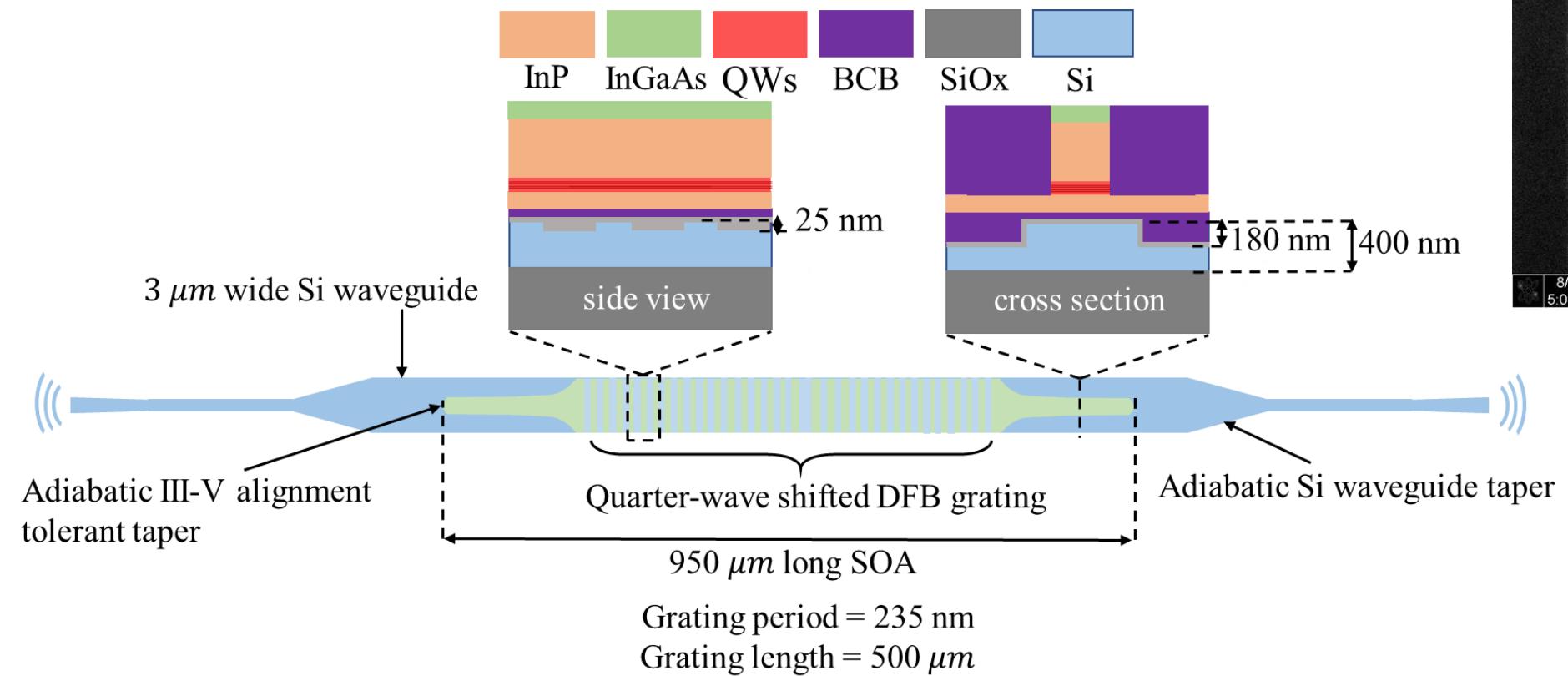
At high on-chip input powers (0 dBm) both the amplifiers have similar NF values.

At low on-chip input powers (-24 dBm) the partial coupling amplifier has lower NF values.



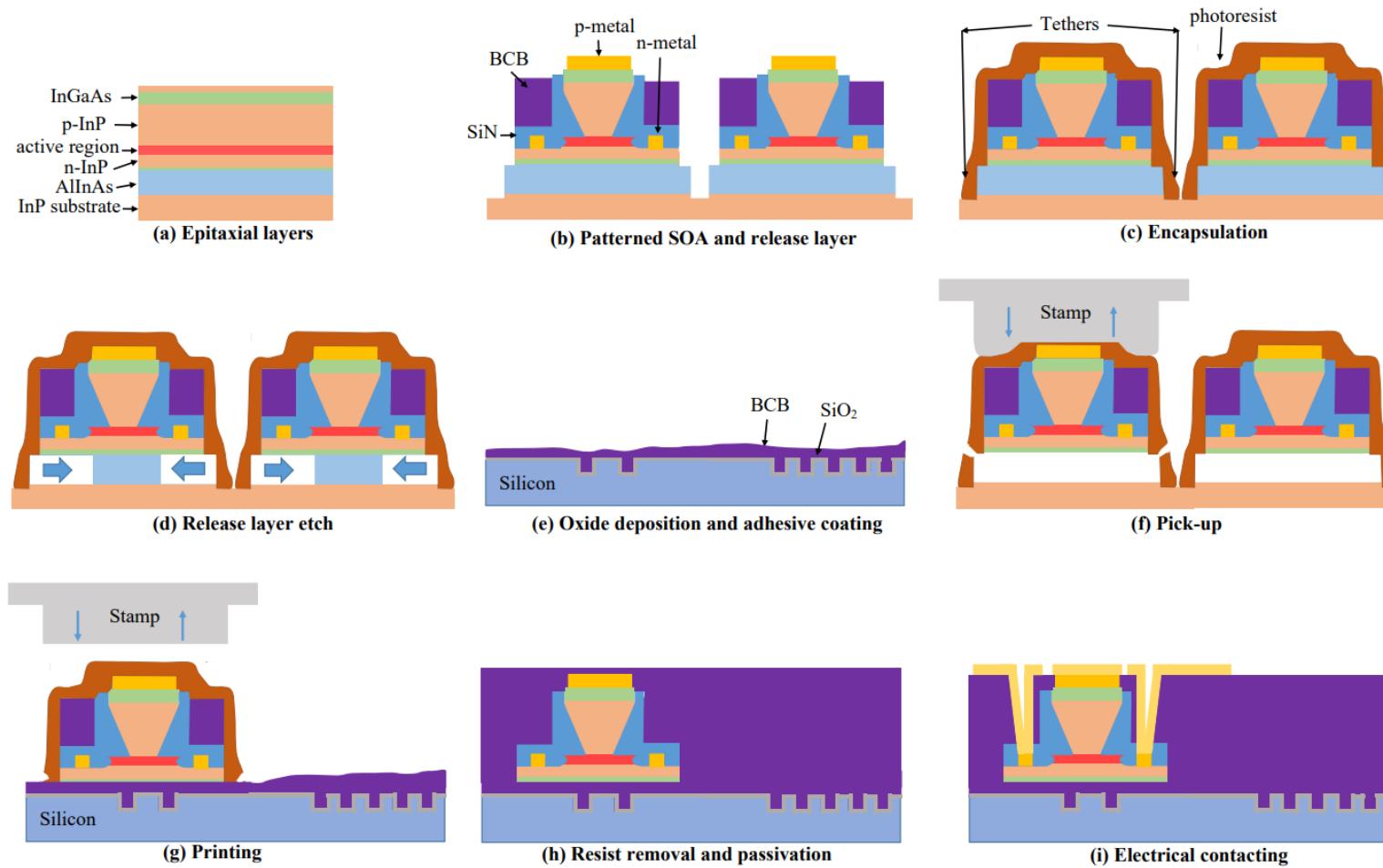
μ TRANSFER-PRINTED DFB LASER

DESIGN OF III-V-ON-SILICON DFB



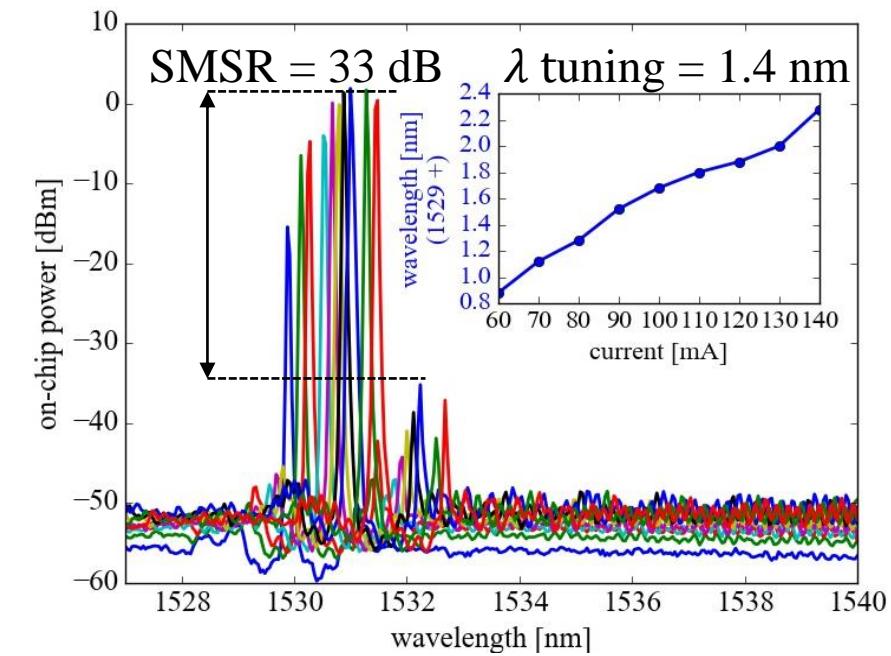
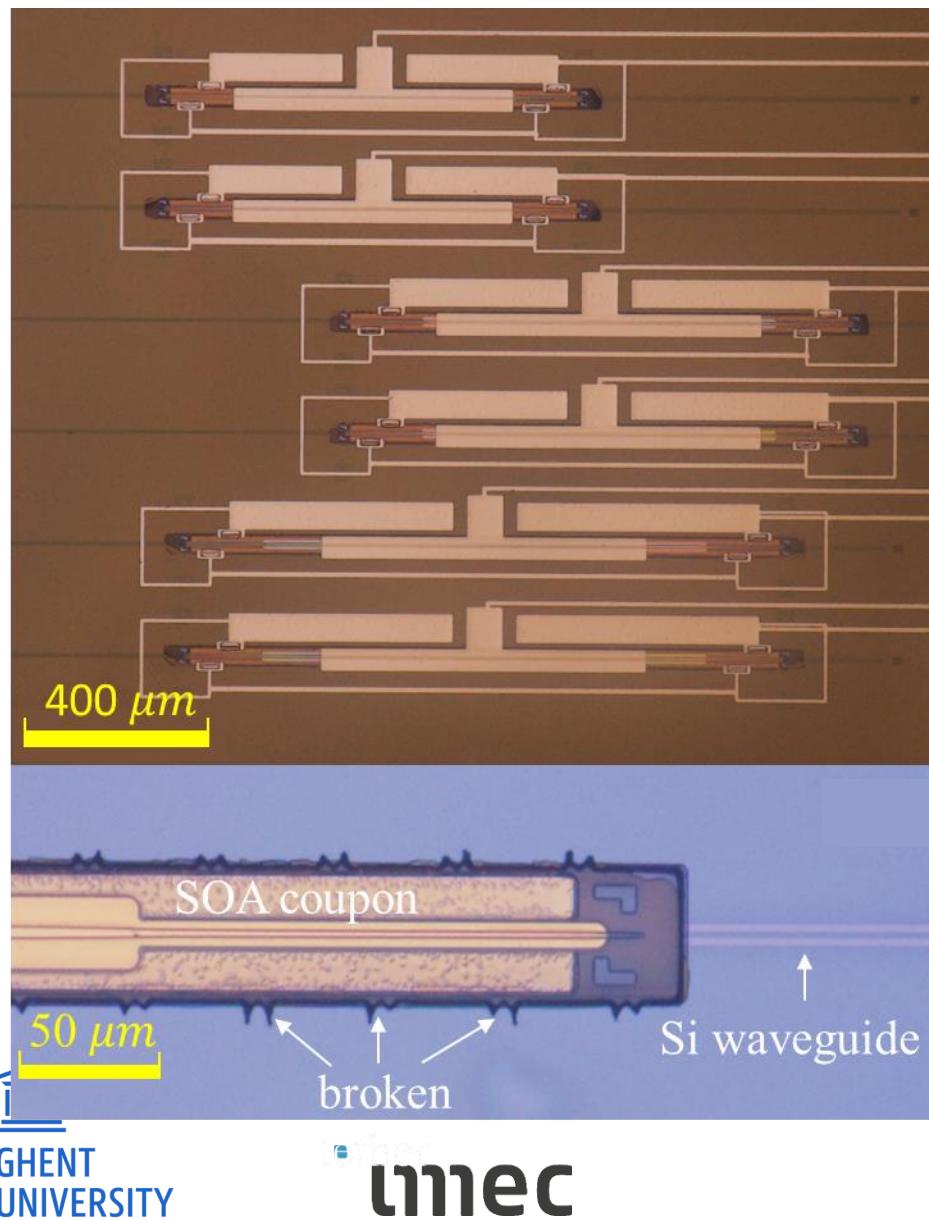
SEM image of DFB grating

FABRICATION PROCESS FLOW

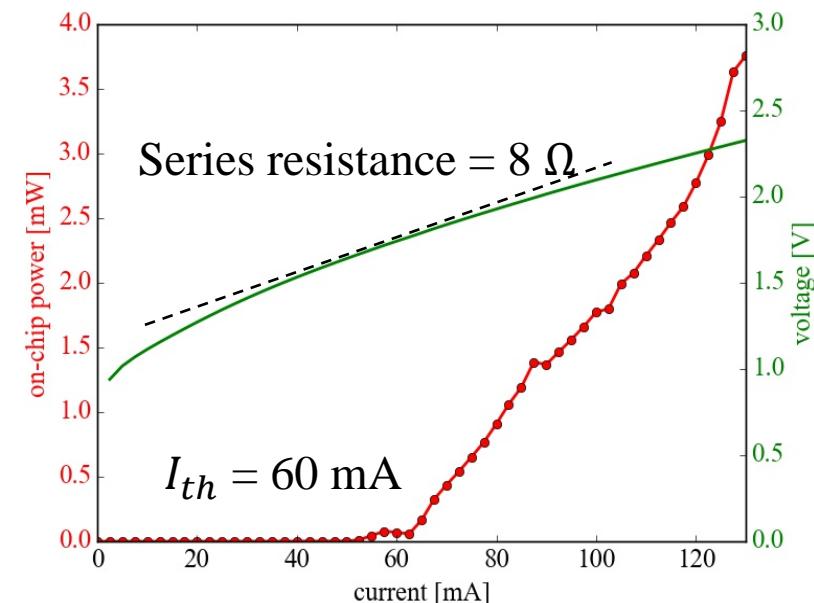


Similar as in the case of SOA demonstration

SINGLE MODE DFB LASER (GEN 1)

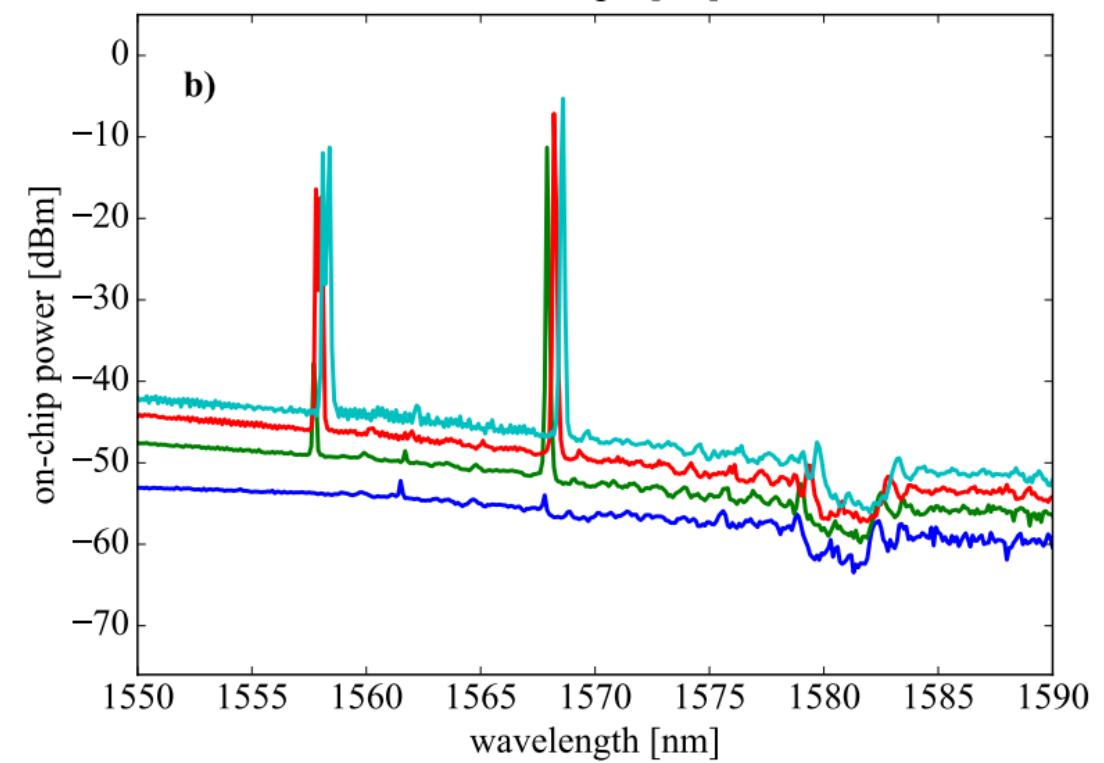
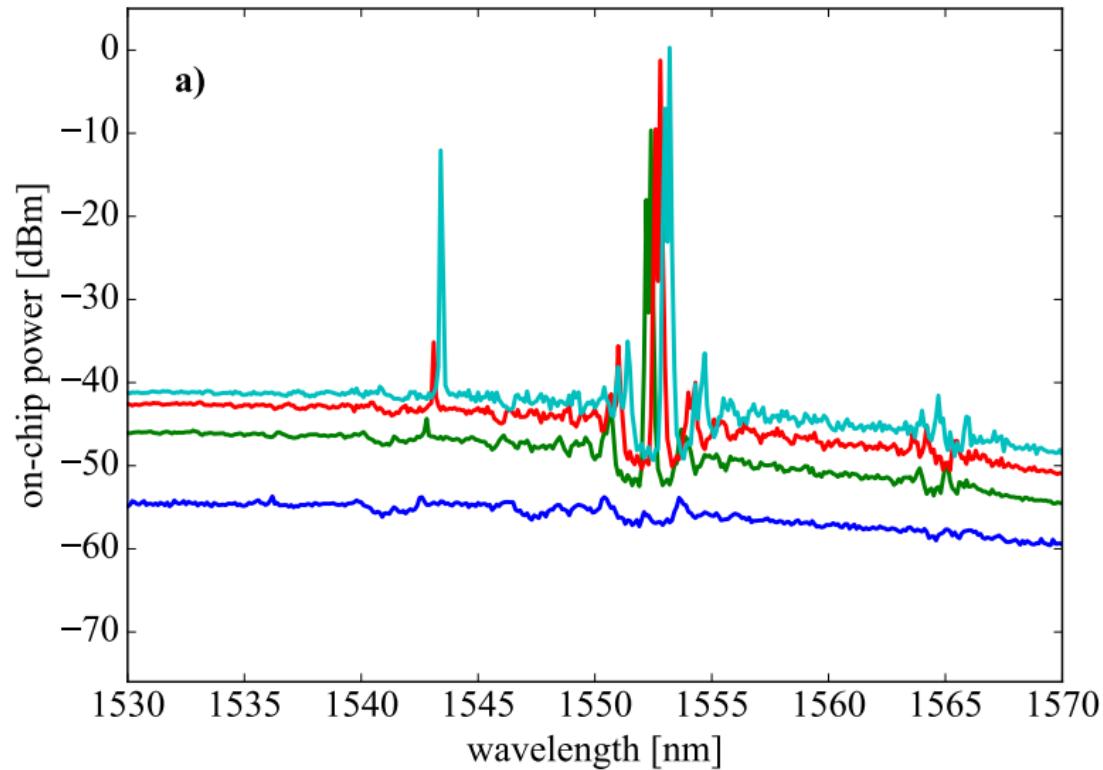


Single-sided output power = 3.75 mW



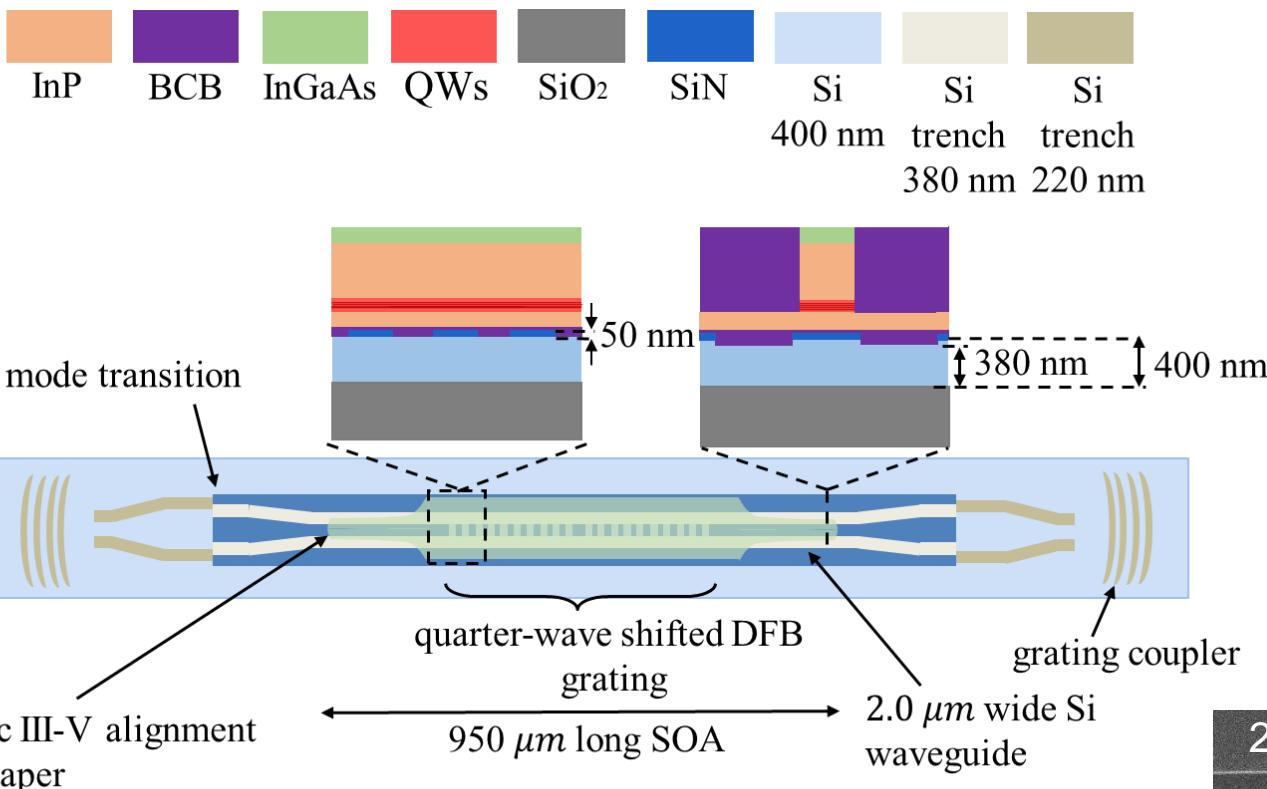
ISSUES WITH GEN 1 DFBS

We want a single laser line in the spectrum at a particular bias current.



Multiple peaks in the spectrum corresponds to higher order transversal modes of the III-V and Si waveguide

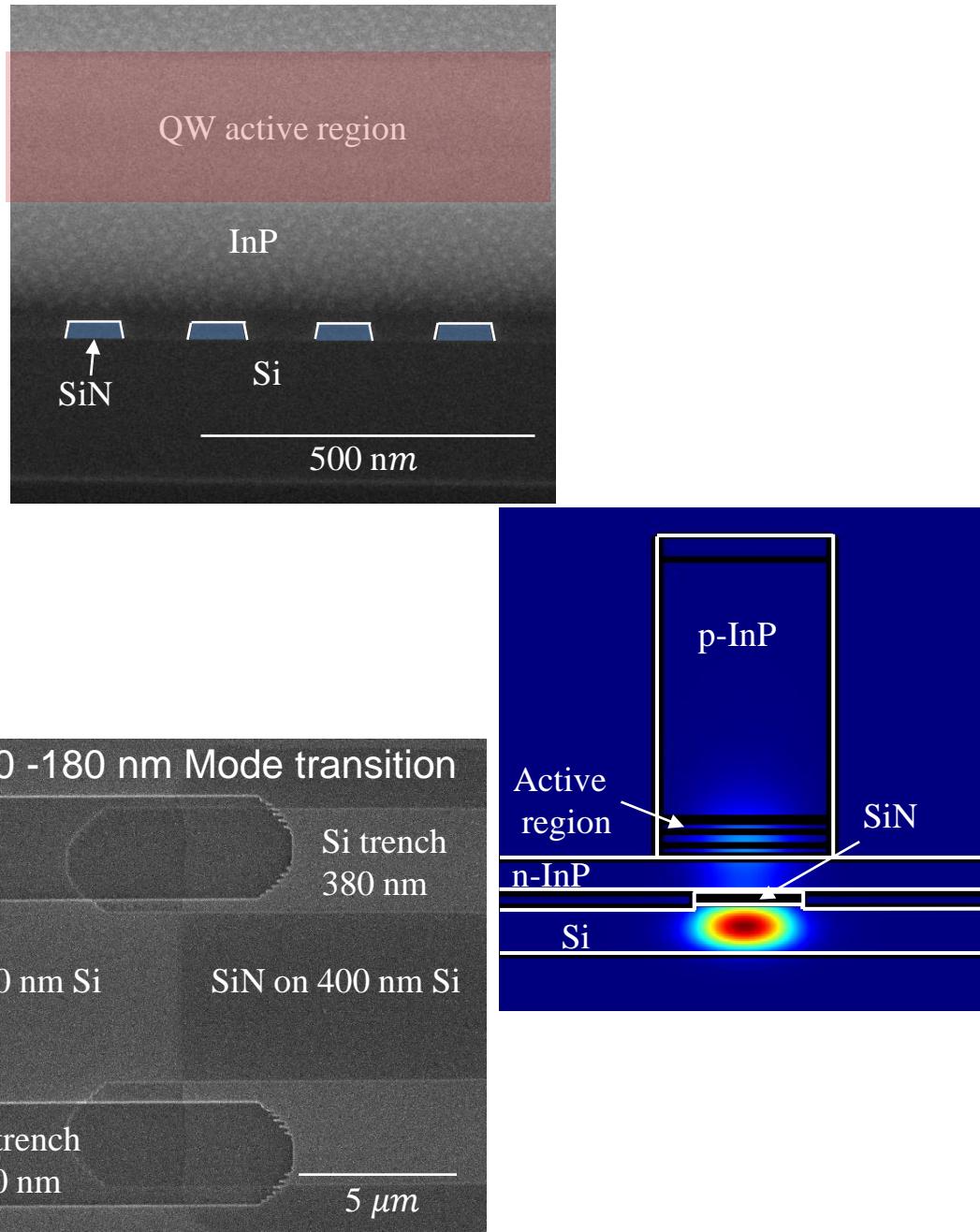
GEN 2 DFB DESIGN



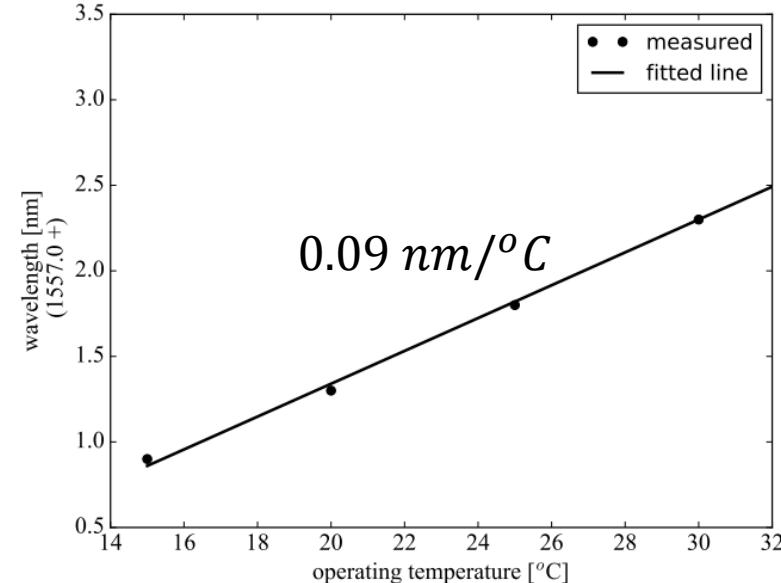
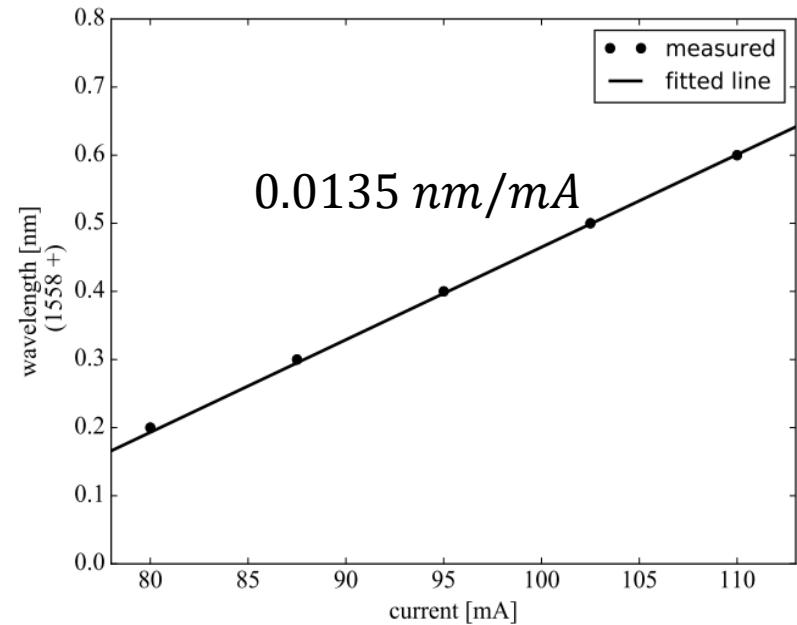
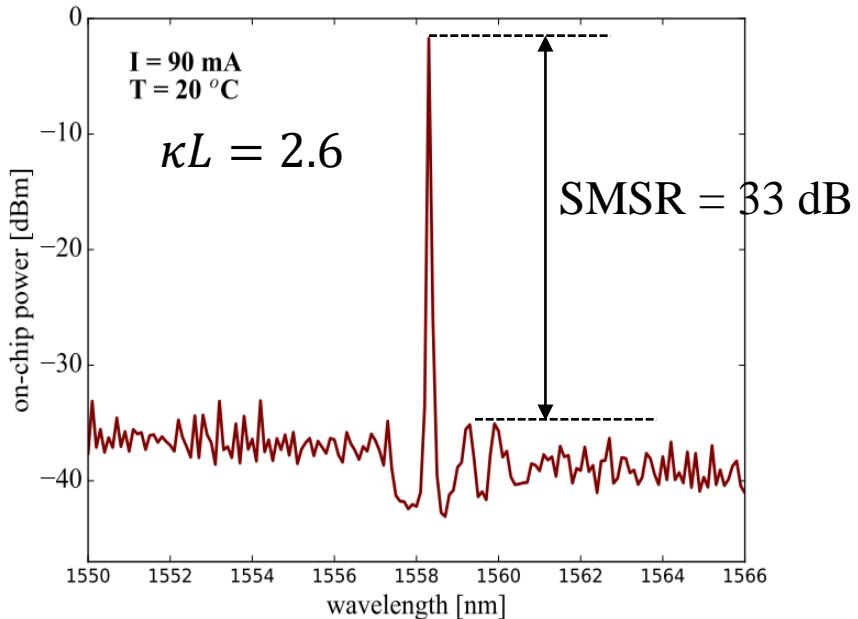
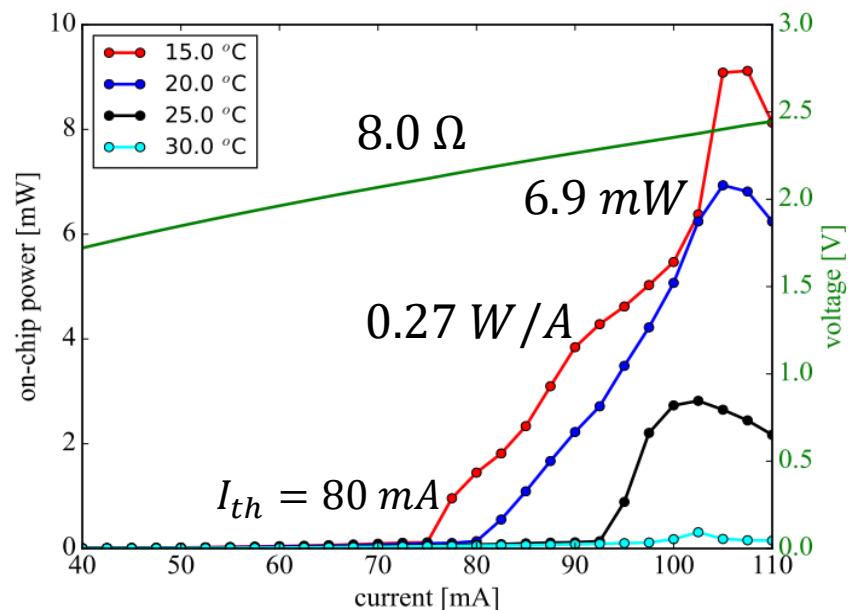
Modifications in Gen 2 design

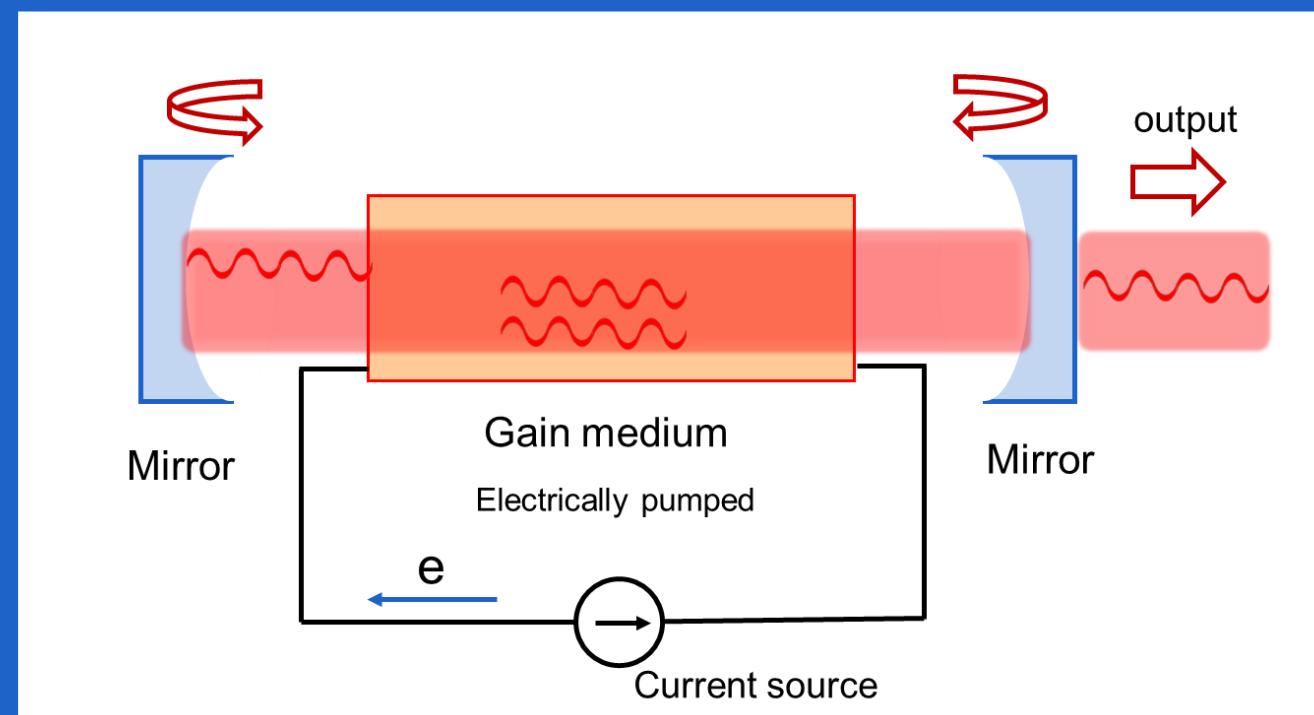
- The etch-depth of the Si waveguide reduced to 20 nm.
- To reduce the κ grating are defined on 50 nm thick SiN

layer deposited on Si.



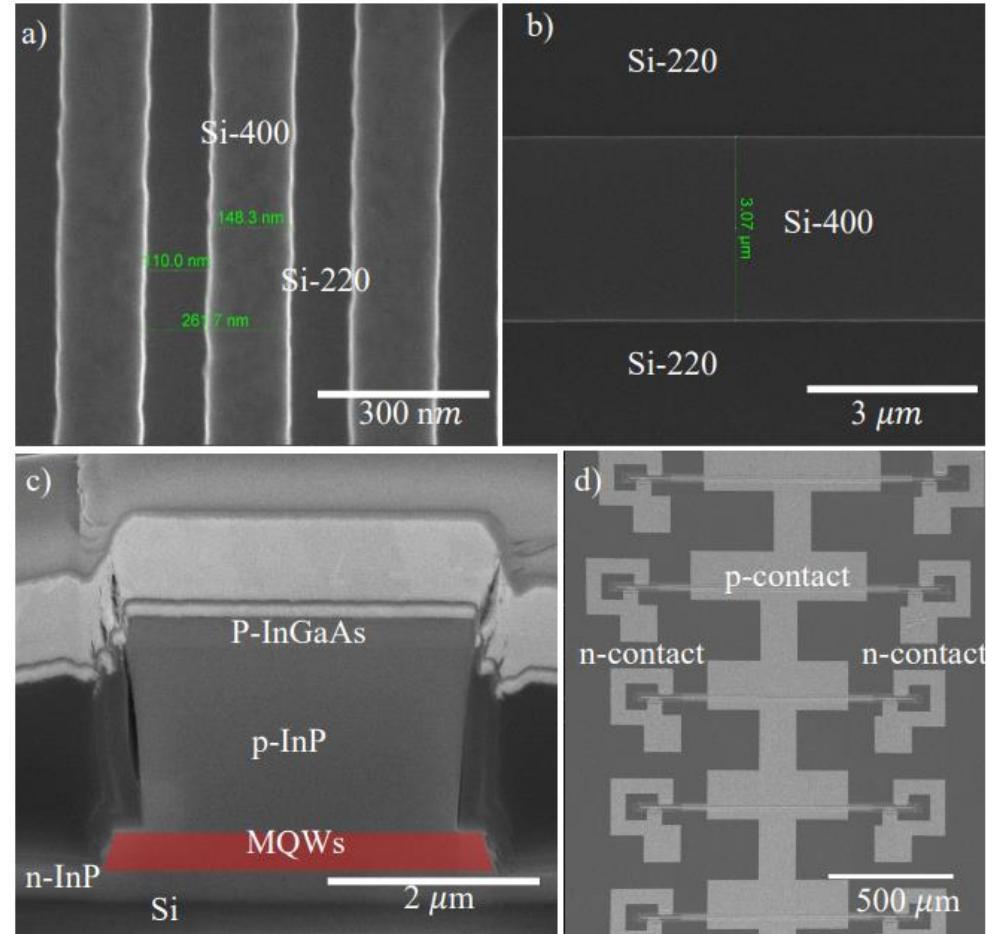
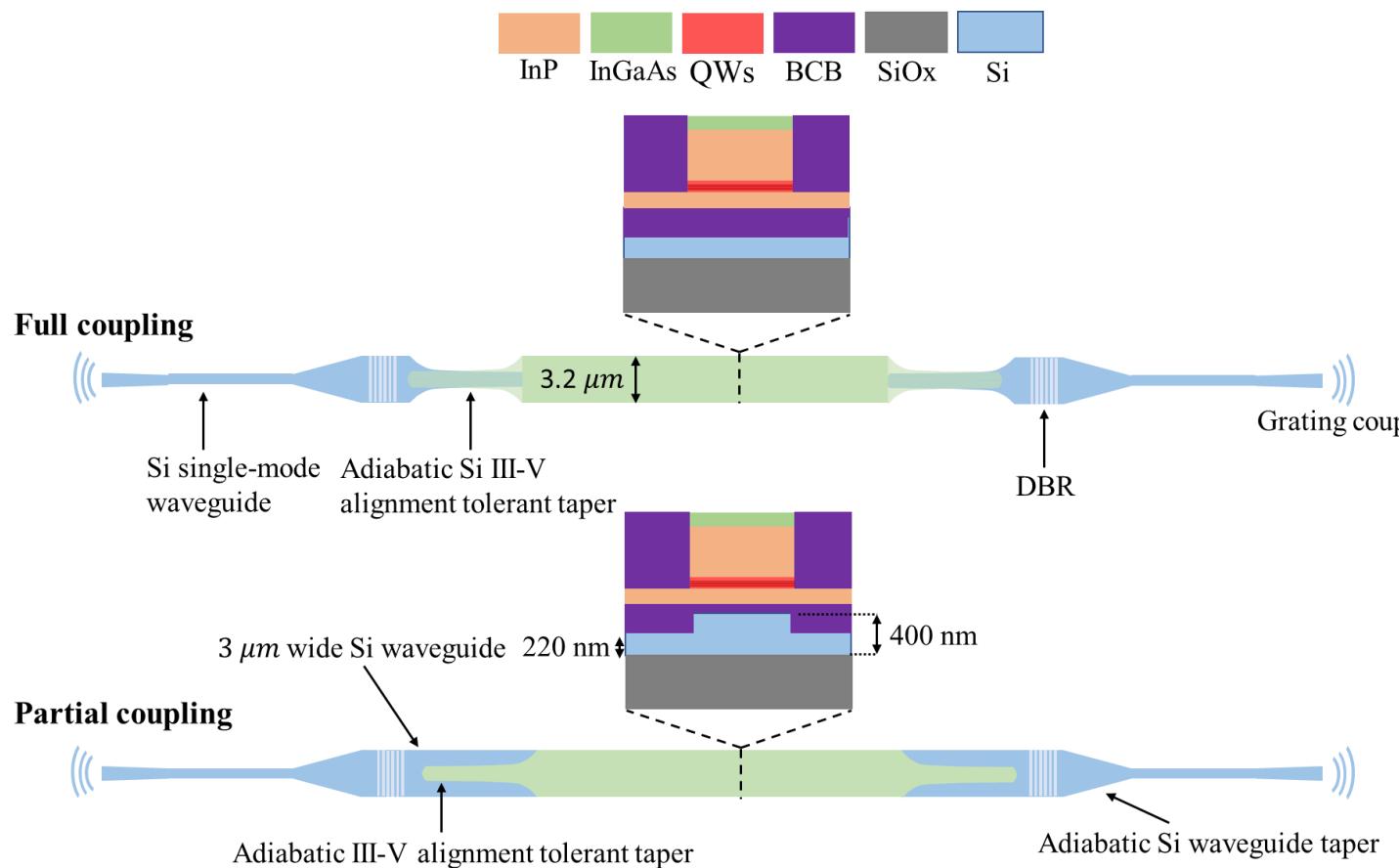
MEASUREMENTS





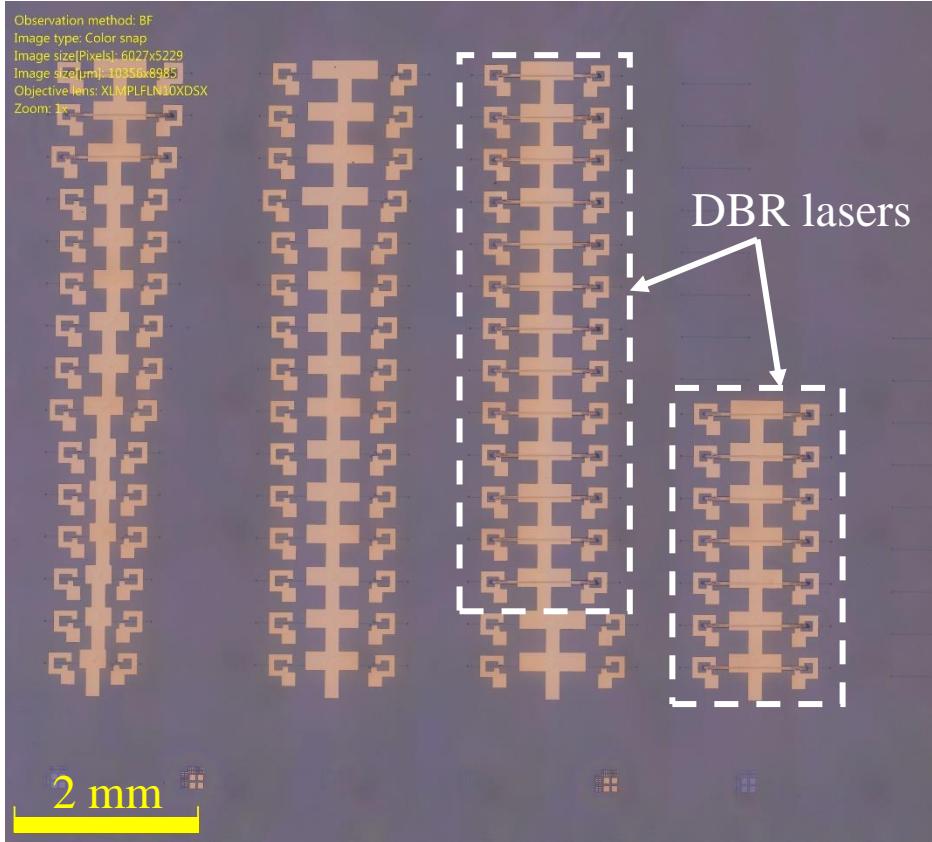
μ TRANSFER-PRINTED DBR LASER

DBR LASERS



Symmetric DBR lasers to study the effect on the threshold current due to lateral misalignment

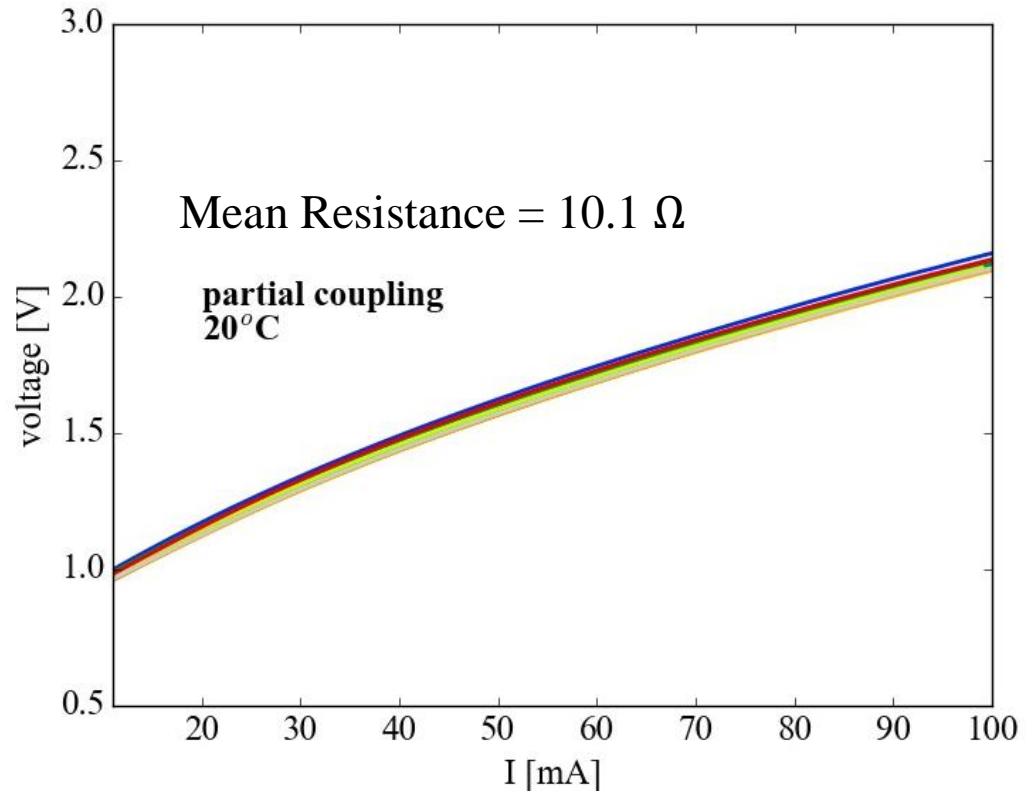
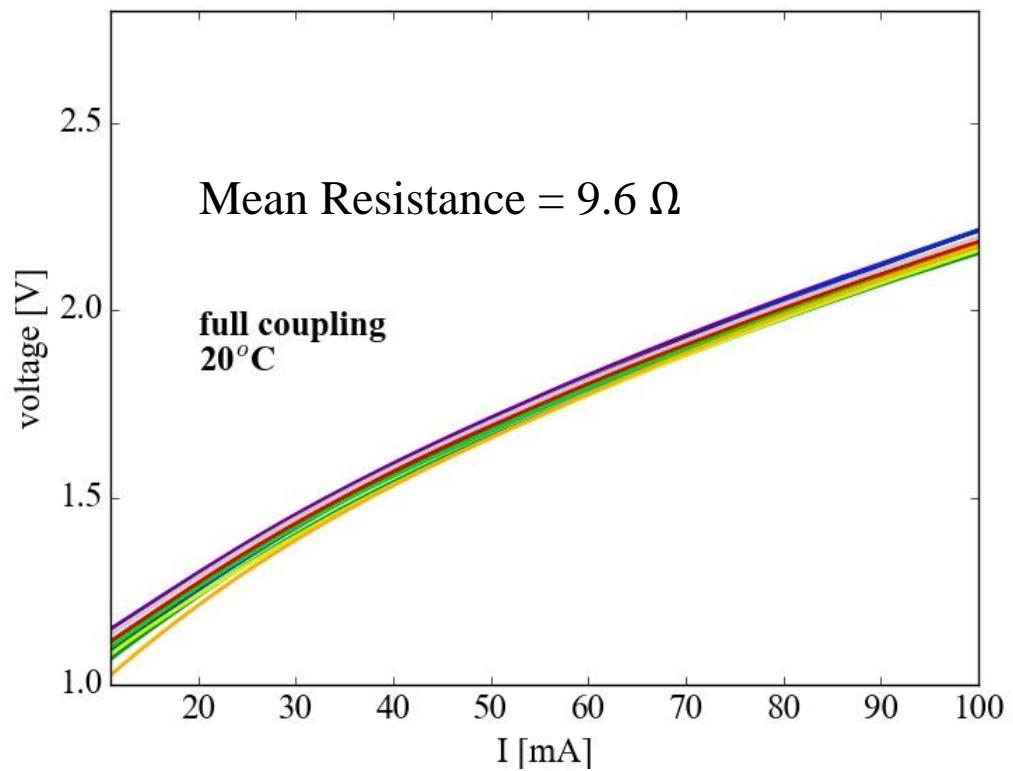
PIC LAYOUT



Array of similar DBR lasers are micro-transfer-printed individually

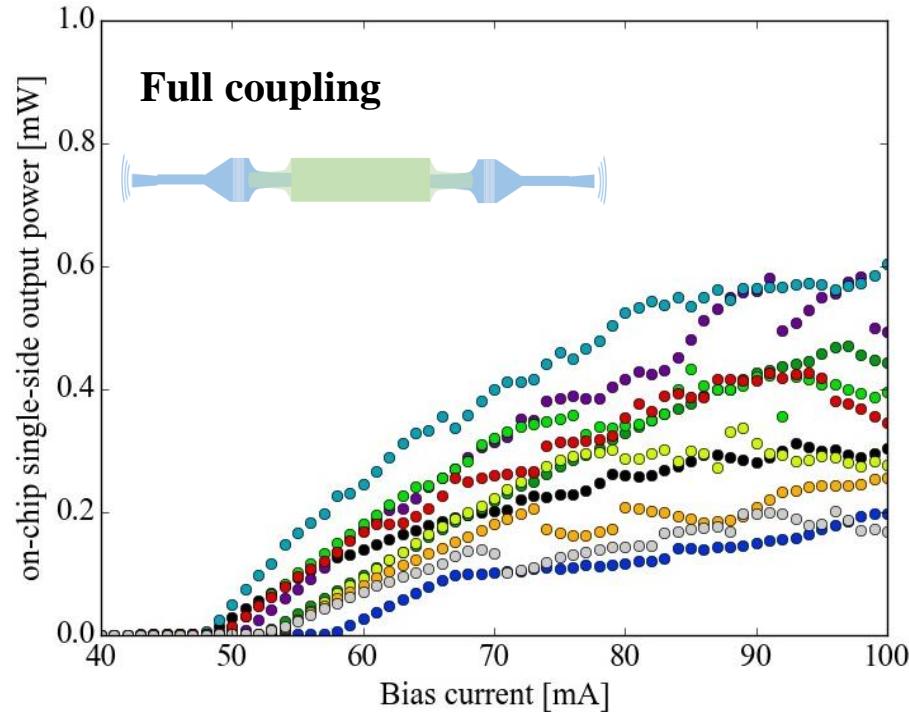
- To study the effect of micro-transfer-printing process on the performance of the lasers (threshold current)
- Misalignment between SOA and Si waveguide can introduce additional losses in the cavity and increase the threshold current

I-V CHARACTERISTICS

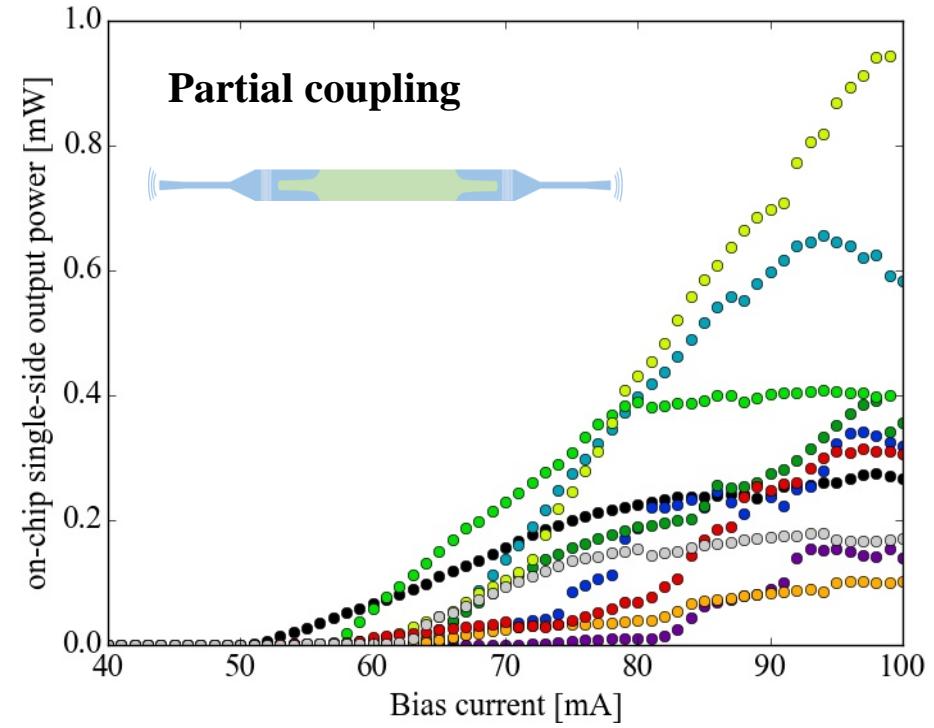


Since the SOAs are identical and processed together on an InP die
➤ They have nominally identical differential resistance

L-I CHARACTERISTICS



Mean threshold current = 51 mA
Standard deviation = 3.24 mA

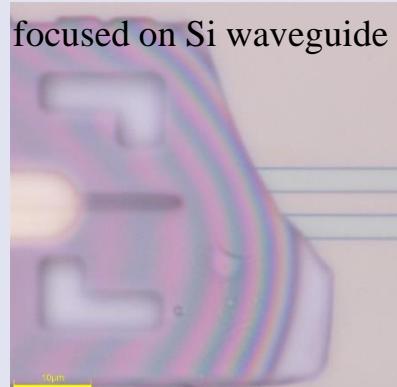
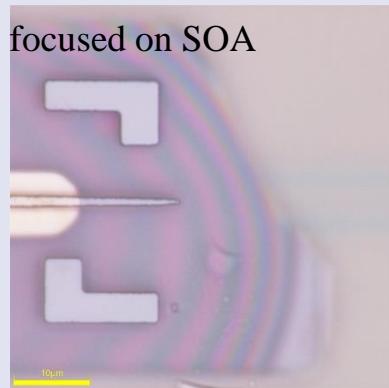


Mean threshold current = 60 mA
Standard deviation = 5.31 mA

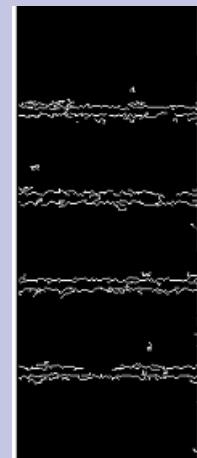
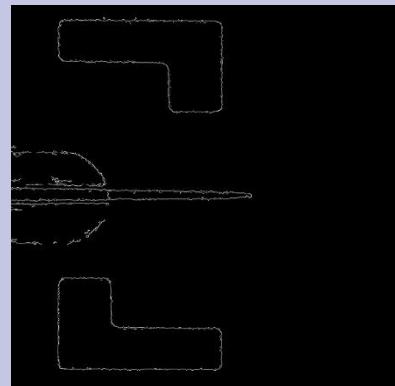
- Large spread in the I_{th} and slope efficiency of partial coupling DBR can be attributed to the variation of the confinement factor in the QW with misalignment
- Moreover, as various transversal modes are supported in the gain section, this can cause the spread to increase further.

MISALIGNMENT CALCULATION

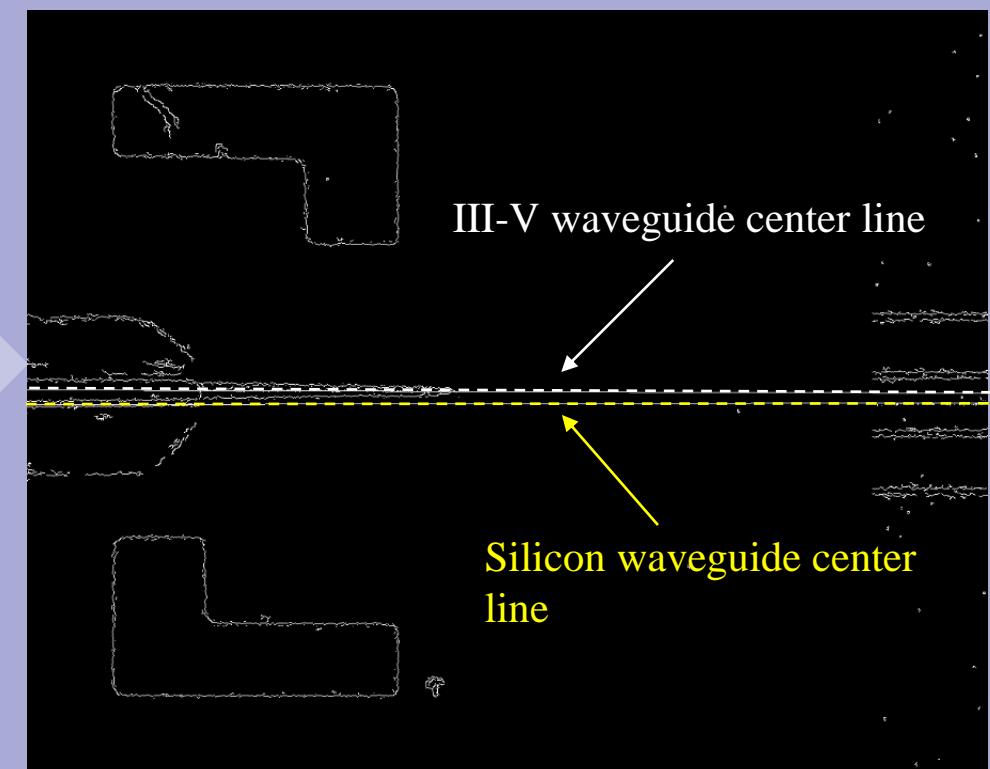
High-resolution microscope images
43 nm per pixel



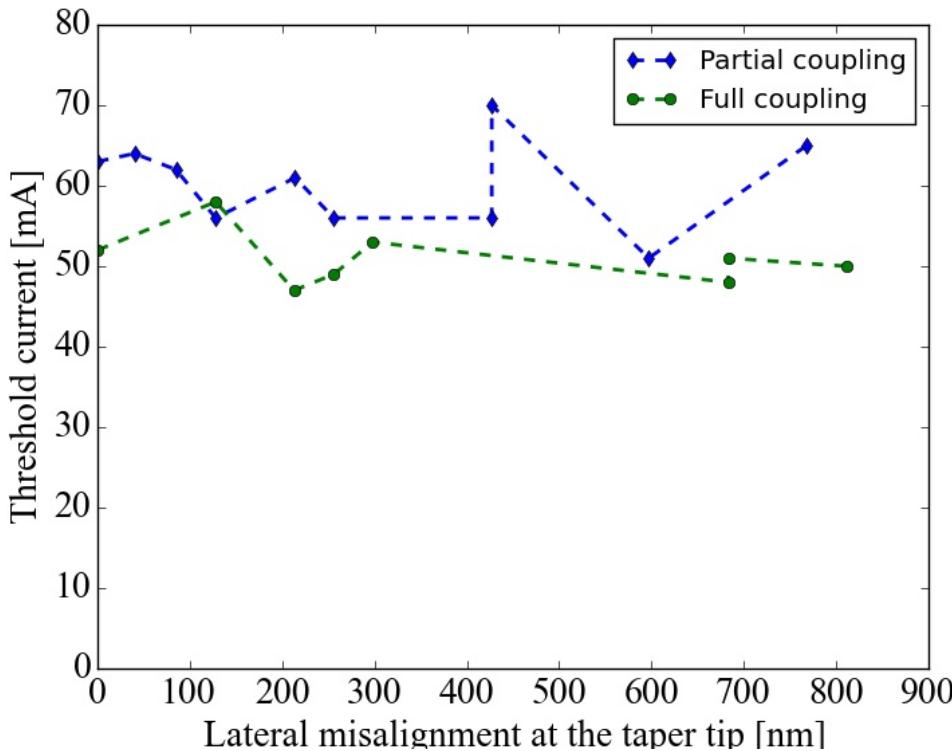
edge detection of III-V and Si
waveguide



Center-line calculation and fitting



THRESHOLD CURRENT AND MISALIGNMENT



- Misalignment and the threshold current shows no correlation which corroborates the alignment tolerant design of the adiabatic couplers.
- Furthermore, the effect of misalignment is insignificant on the loss as compared to the waveguide loss (~ 40 dB/cm) in the III-V-on-Si waveguide.

FUTURE OUTLOOK

- Adding contact pads to the coupons for electrical testing and to eliminate processing steps after printing.
- Integration in complex foundry platforms such as ISSIP50G and Ligentec low loss SiN platform
- Integration of best of class devices from multiple material systems such InP lasers, LiNbO_3 modulators, and low loss SiN waveguides.

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Thank you for your attention

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